

**ISPD 2013**  
**Commemoration for Professor Y. Kajitani**

# **Practicality on Placement Given by Optimality of Packing**

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# Today's Talk

## 1) Rect. packing-base analog placement

- ➔ Sequence-pair Packing
- ➔ Constraint-driven Optimization

## 2) With or without packing scenario, how do we develop analog placement?

- ➔ Analytical Analog placement with proximity constraints
- ➔ Comparison : w/ and w/o topological packing technique



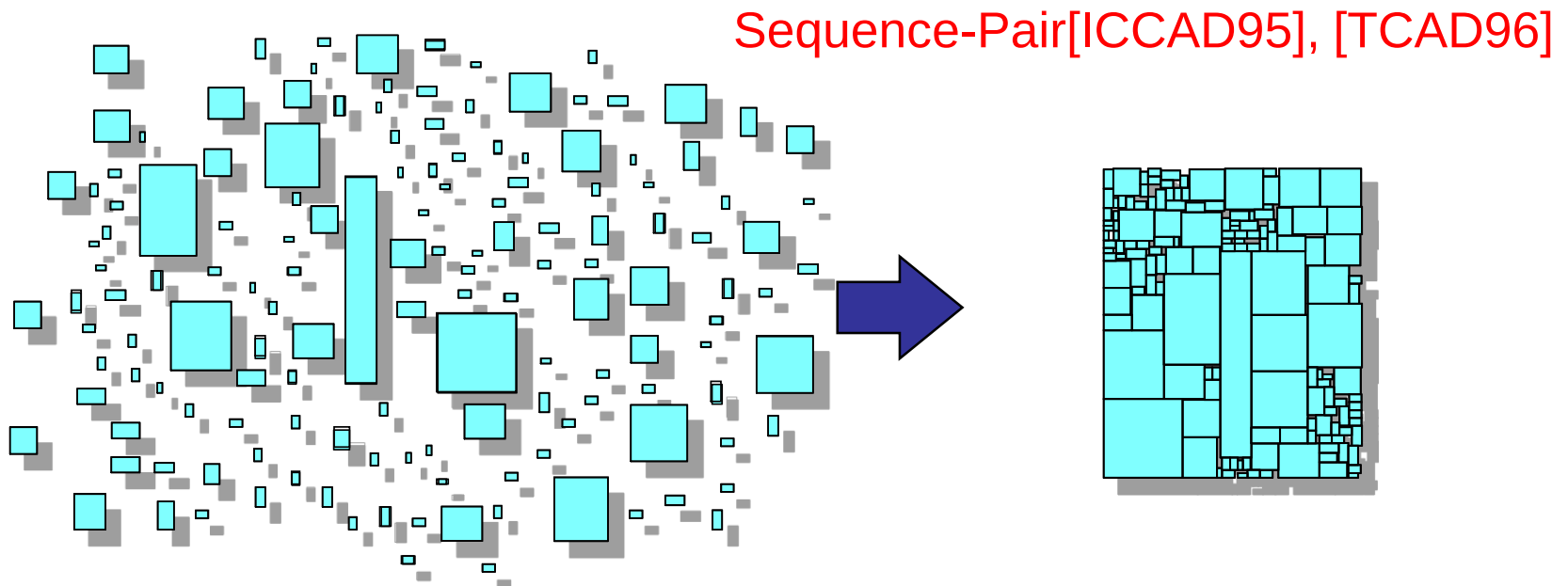
# 2D Rect. Packing

INPUT: A set of rectangles, each of which has width and height

OUTPUT: A placement of rectangles

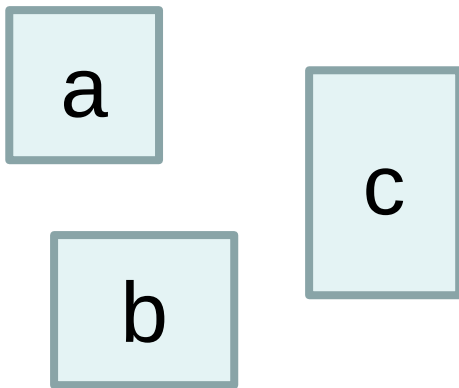
SUBJECT TO: No overlapping of any pair of rectangles

OBJECTIVE: Minimize bounding box of all the rectangles

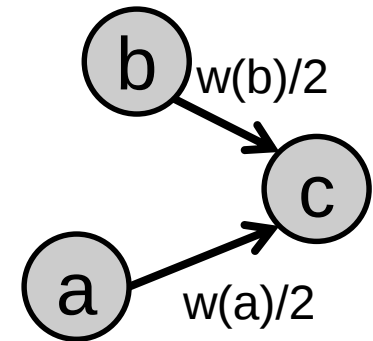
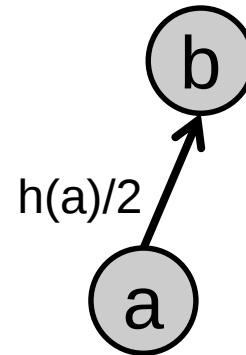


# Topological Representation and Constraint Graphs

Placement  
(w/o any overlapping):



Constraint graphs:



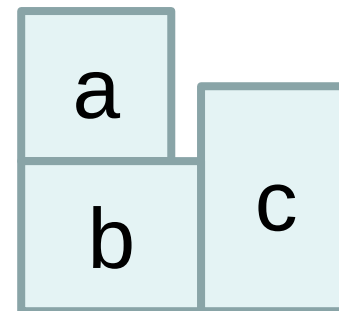
vertical const. graph    horizontal const. graph

NOTE:  $G_v$ ,  $G_h$  are weighted DAG

Topological description:

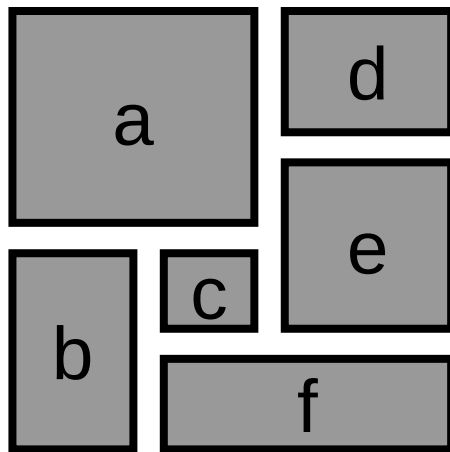
- a is left-of c (c is right of a)
- b is left-of c (c is right of b)
- b is below a (a is above b)

Compacted placement:



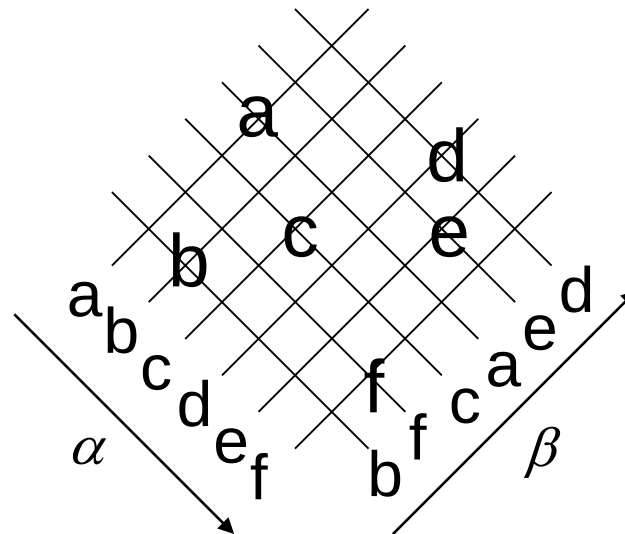
# Sequence-Pair(1)

*Placement*



*Sequence-Pair*

$SP = (\alpha, \beta) = (abcdef, bfcaed)$



*Oblique-Line-Grid: Equivalent Representation of SP*

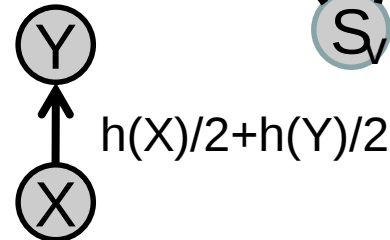
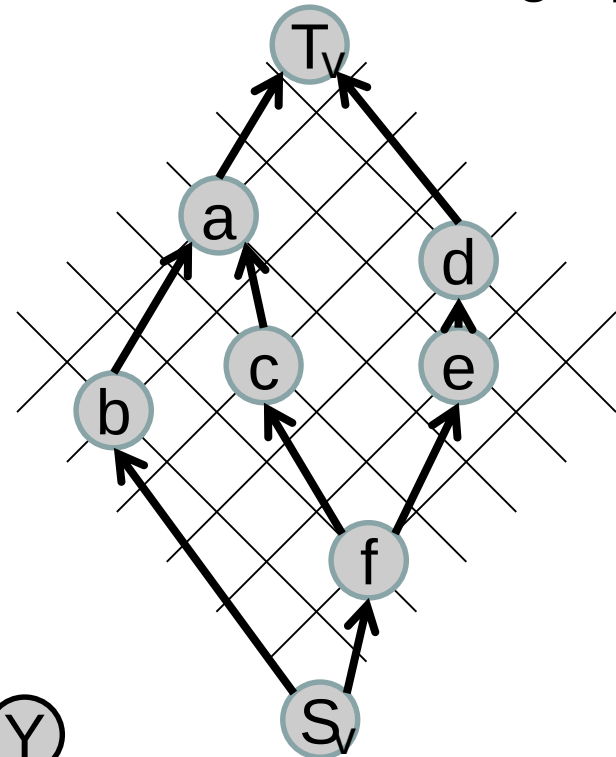
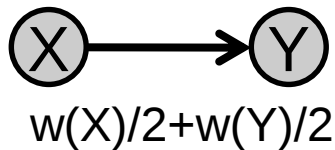
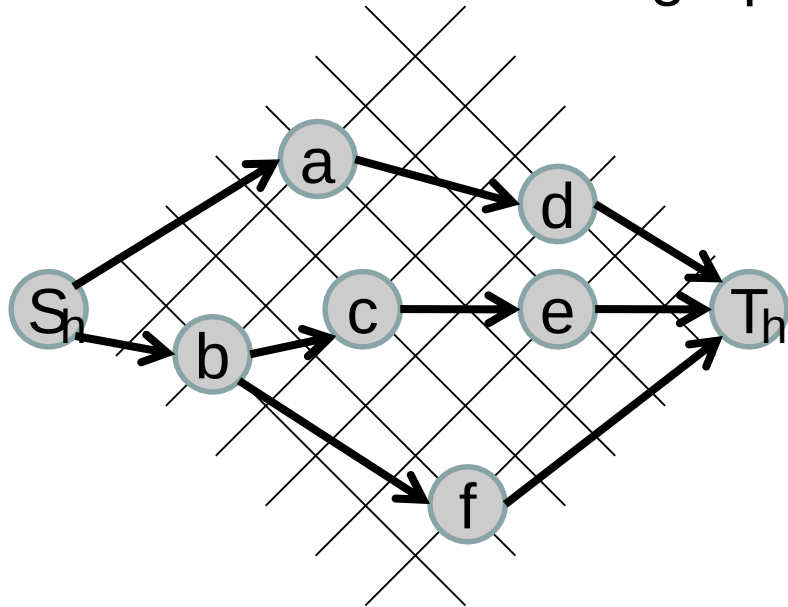
$\alpha^{-1}(X)$  : position of  $X$  in  $\alpha$      $\alpha^{-1}(X) < \alpha^{-1}(Y), \beta^{-1}(X) < \beta^{-1}(Y) \Leftrightarrow X$  is left-of  $Y$

$\beta^{-1}(X)$  : position of  $X$  in  $\beta$      $\alpha^{-1}(X) > \alpha^{-1}(Y), \beta^{-1}(X) < \beta^{-1}(Y) \Leftrightarrow X$  is below  $Y$



# Sequence-Pair(2)

G<sub>h</sub>: horizontal constraint graph G<sub>v</sub>: vertical constraint graph



NOTE: w(X) , h(X): width, height of X



# Sequence-Pair(3)

1. **Every placement** corresponds to a **sequence-pair**
2. Packing according to constraint graphs can generate a minimal area placement under the same topological description
3. A solution space induced by sequence-pairs always includes **an optimum placement** with respect to area

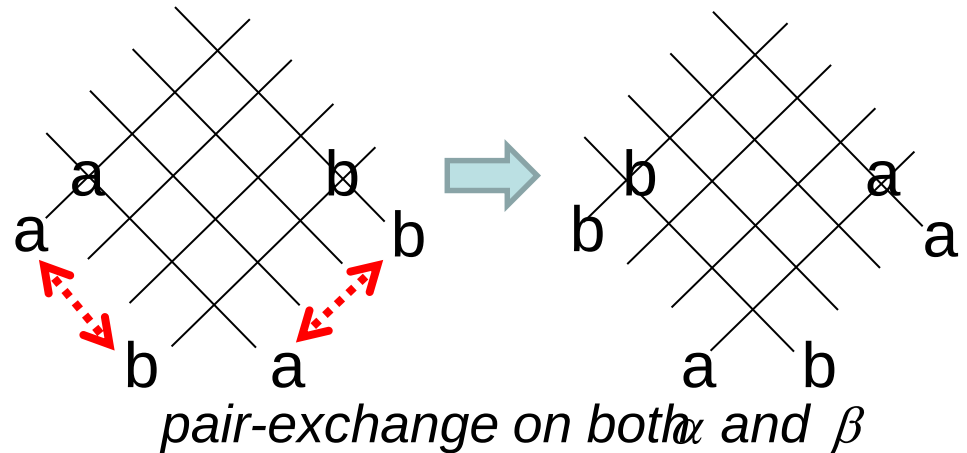


# Sequence-Pair(4)

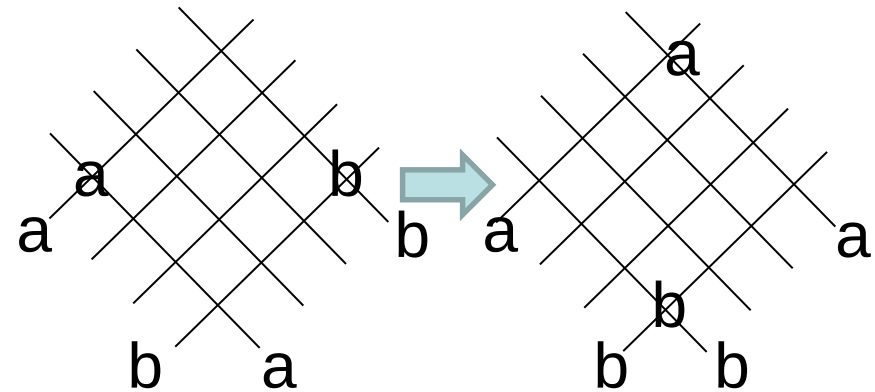
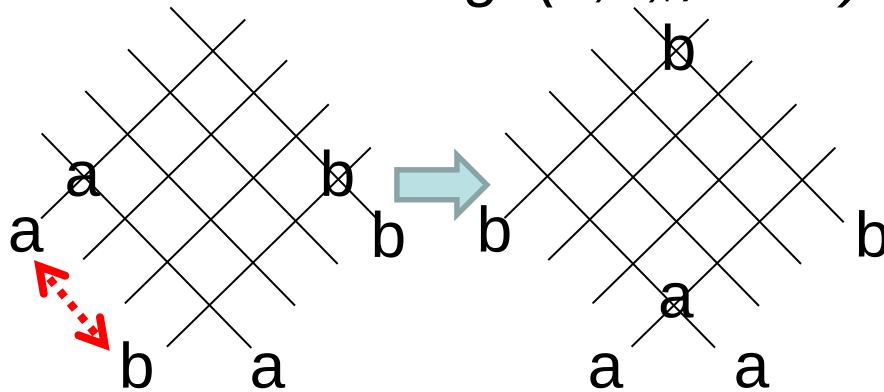
## Application to simulated annealing

Moves:

1.  $FullExchange(a,b)$ :

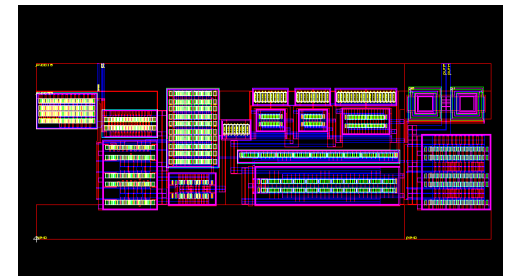


2.  $HalfExchange(a,b, \beta)$ :

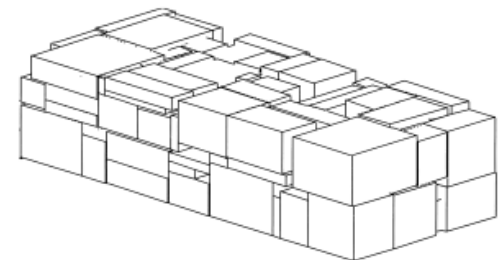
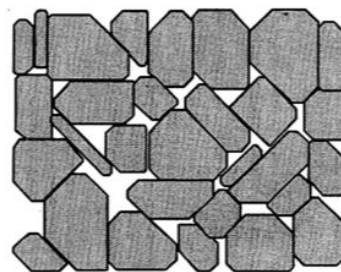


# Practical Applications of Packing

- Building block placement
- Floorplanning for large scale circuits
- **Analog placement**
- 3D Cube packing
- Polygon packing
- Scheduling for dynamic reconfigurable system



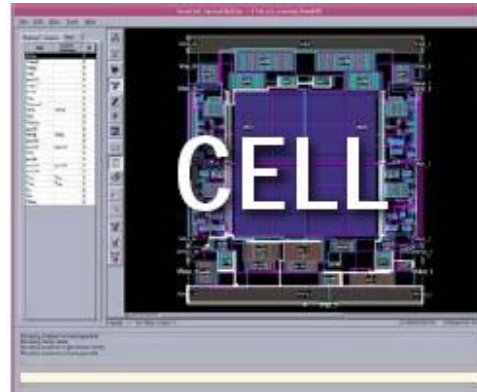
...



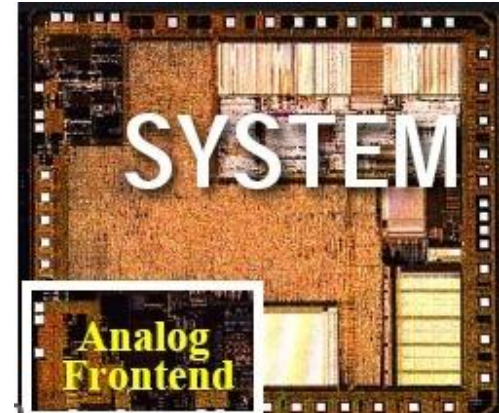
# Analog Placement



Device Generation



Cell Design



Block Design

Each Placement...



# Analog Placement

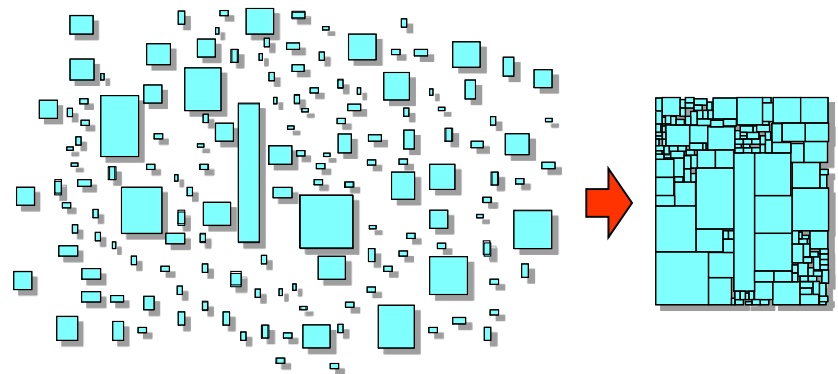
- **Geometry-based placement**
  - ILAC [CICC88], KOAN/ANAGRAM [ICCAD88]
  - larger area and time consuming
- **Topology-based placement (modern)**
  - BSG, Sequence-Pair, O-tree, B\*-tree, TCG-S,  
...
  - Constraint-driven
    - symmetry, common-centroid, alignment and others
  - smaller area and rapid convergence



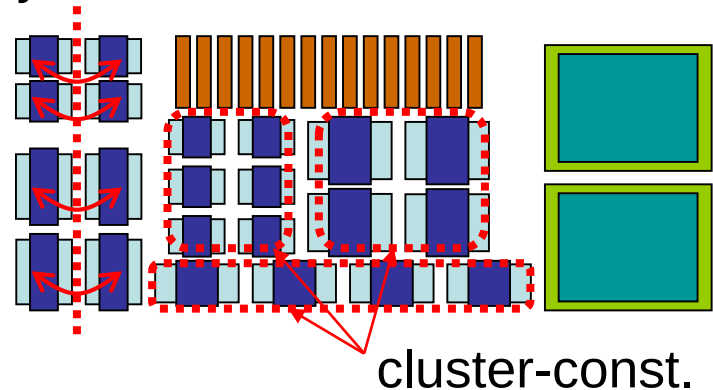
# Constraint-driven Placement

1. Formulation as a rectangle packing problem
2. Extensions under constraints

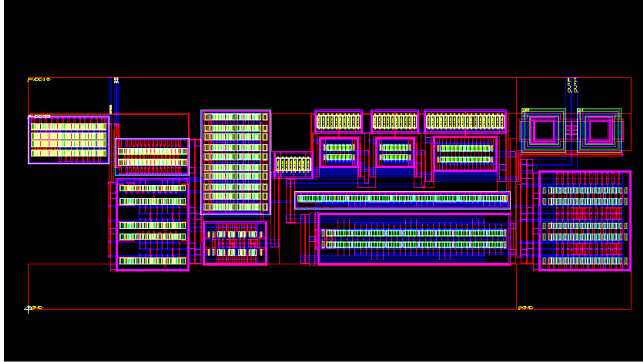
- Separation Constraint
- Alignment Constraint
- Abutment Constraint
- Boundary Constraint
- Symmetry Constraint
- Preplaced Constraint
- Range Constraint
- Cluster Constraint



symm-const.



# Our Works in Constraint-driven Analog Layout



- **Placement**

- ASPDAC04, GLSVLSI04, IEICE04, ISVLSI06a, ASPDAC09, ASPDAC08
- AMPER produced by JEDAT

- **Routing**

- GLSVLSI05, IEICE06

- **Compaction**

- ASPDAC02, ISVLSI06b
- GRANA produced by JEDAT

[ICCAD95] H.Murata, K.Fujiyoshi, S. Nakatake, Y.Kajitani, “*Rectangle-Packing Based on Module Placement*”, ICCAD95, pp.472-479, 1995.  
[TCAD96] VLSI H.Murata, K.Fujiyoshi, S.Nakatake, Y.Kajitani, “*Module Placement Based on Rectangle-Packing by the Sequence-Pair*”, IEEE Trans. on CAD, vol.15, No.12, pp.1518-1524, 1996.

[ASPDAC02] Y.Kubo, S.Nakatake, Y.Kajitani, M.Kawakita, “*Explicit Expression and Simultaneous Optimization of Placement and Routing for Analog IC Layouts*”, ASPDAC02, pp.467-472, 2002.

[ASPDAC04] T.Noijima, X.Zhu, Y.Takashima, S.Nakatake, Y.Kajitani, “*Multi-Level Placement with Circuit Schema Based Clustering in Analog IC Layouts*”, ASPDAC04, pp.406-411, 2004.

[GLSVLSI04] T.Noijima, X.Zhu, Y.Takashima, S.Nakatake, Y.Kajitani, “*A Device-Level Placement with Multi-Directional Convex Clustering*”, GLSVLSI04, pp.196-201, 2004.

[IEICE04] T.Noijima, X.Zhu, Y.Takashima, S.Nakatake, Y.Kajitani, “*A Device-Level Placement with Schema Based Clusters in Analog IC Layouts*”, IEICE Trans. on Fundamentals, Vol.E87-A, No.12, pp.3301-3308, 2004.

[IEICE06] N. Fu, S. Nakatake, Y. Takashima, Y. Kajitani, “*The Oct-Touched Tile: A New Architecture for Shape-Based Routing*”, IEICE Trans. on Fundamentals, Vol.E89-A, No.2, pp.448-445, 2006 .

[ISVLSI06a] N Fu, S. Nakatake, M. Mineshima, “*Multi-SP: A Representation with United Rectangles for Analog Placement and Routing*”, ISVLSI06, pp.38-43, 2006.

[ISVLSI06b] T.Noijima, S.Nakatake, T.Fujimura, K.Okazaki, Y.Kajitani, N.Ono, “*Adaptive Porting of Analog IPs with Reusable Conservative Properties*”, ISVLSI06, pp.18-23, 2006.

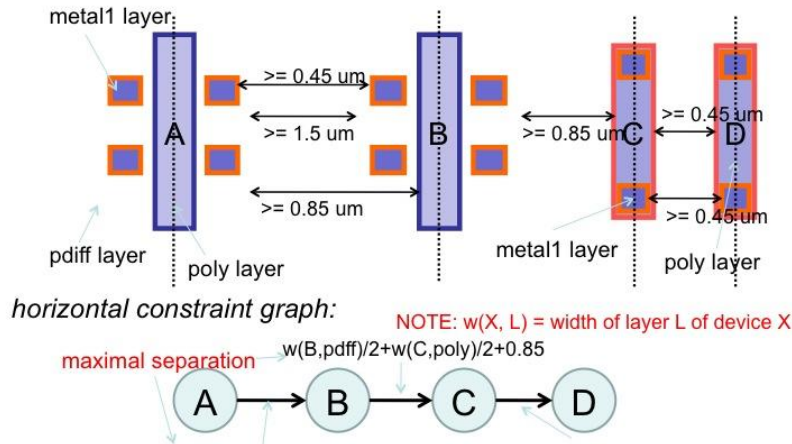
[ASPDAC07] S.Nakatake, “*Structured Placement with Topological Regularity Evaluation*”, ASPDAC07, pp.215-220, 2007.

[ASPDAC08] Q.Dong, S.Nakatake, “*Constraint-Free Analog Placement with Topological Symmetry Structure*”, ASPDAC08, pp.186-191, 2008.

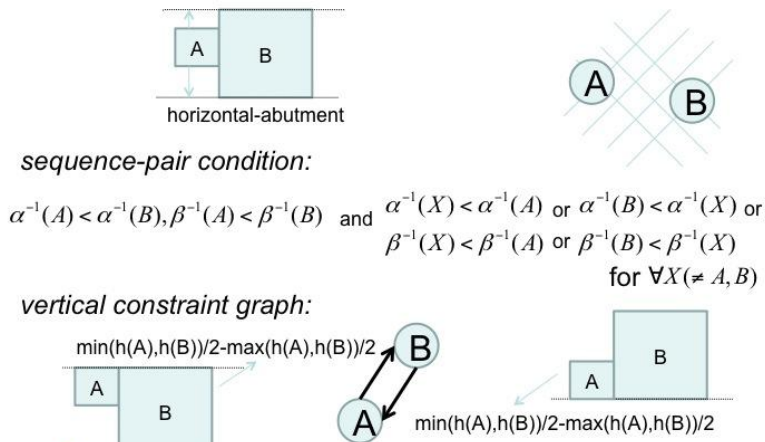


# Analog Constraint Formulation

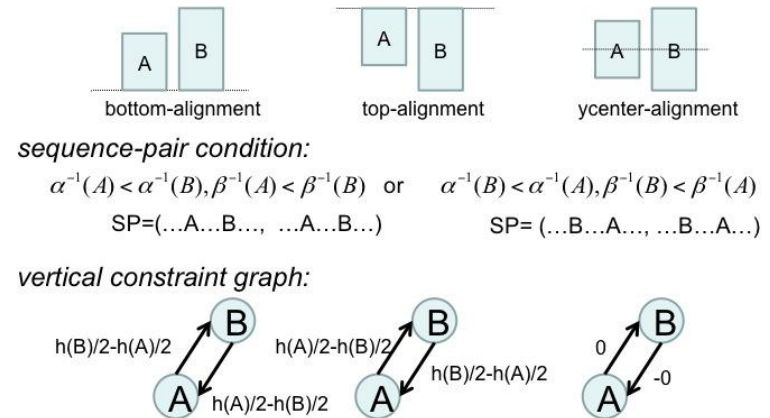
## Separation Constraint



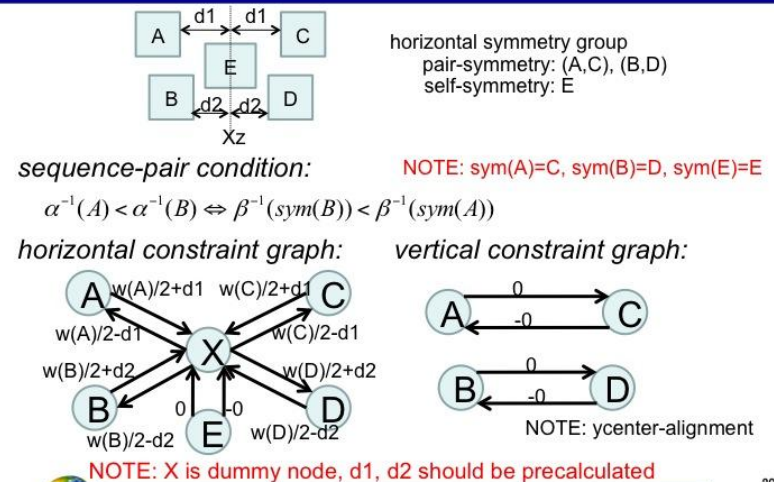
## Abutment Constraint



## Alignment Constraint



## Symmetry Constraint

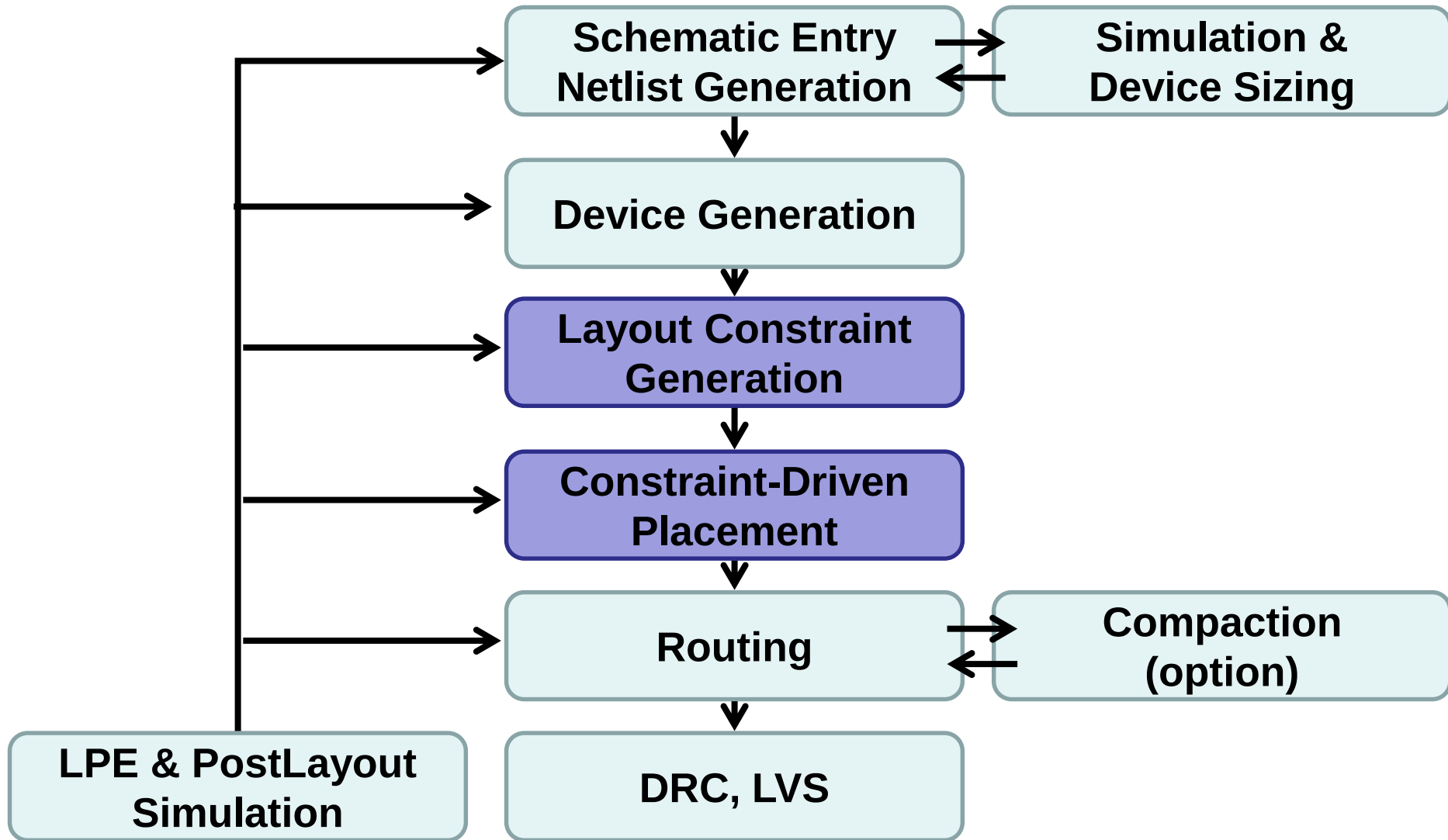


# Objective and Optimization

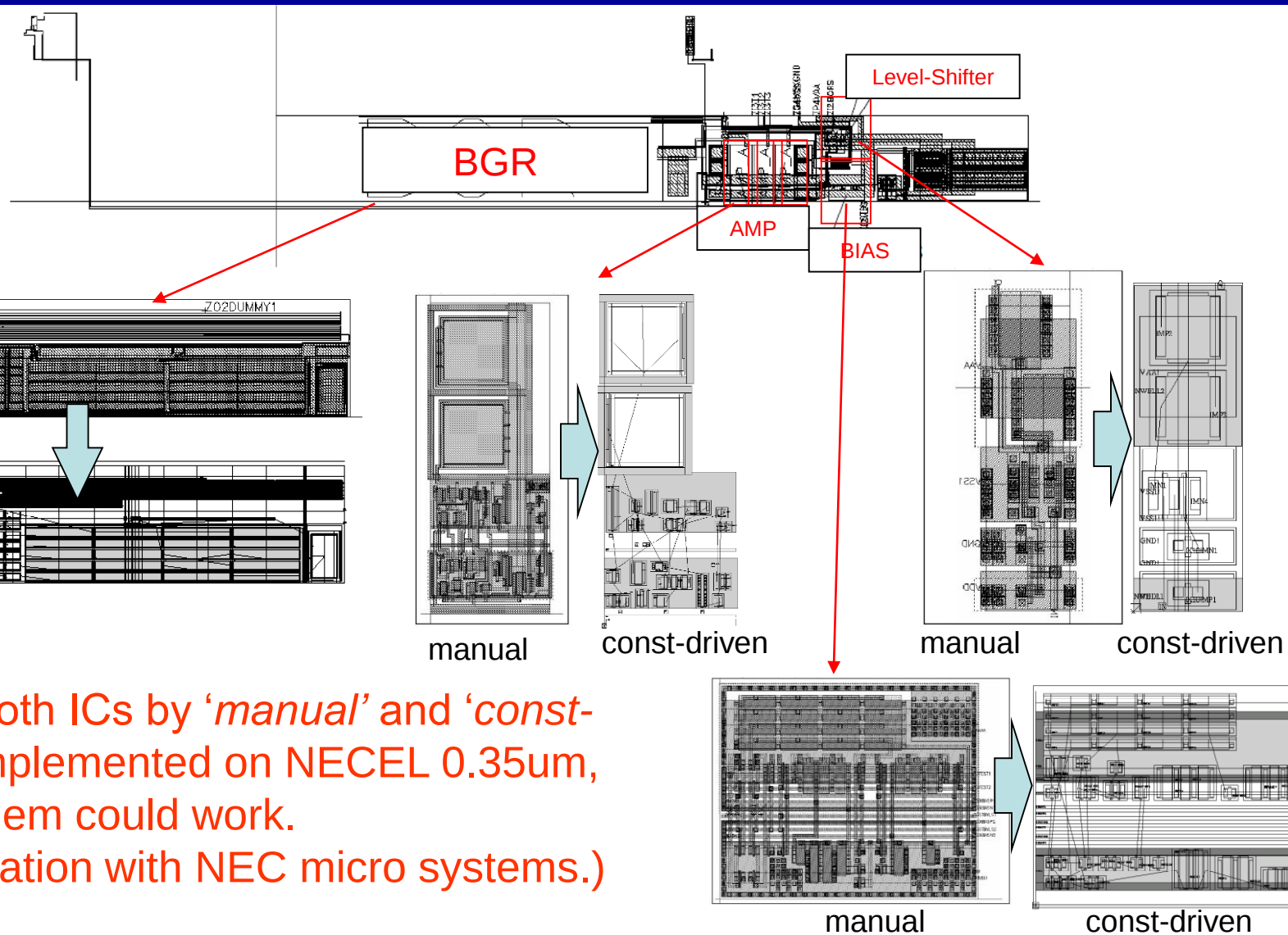
- Objective: Area + Wirelength (HPWL or MST)
- Framework: Simulated Annealing
  - Moves
  - Feasibility Check
    - Topological Checking → sequence-pair conditions
    - Geometrical Checking → no positive cycle



# Design Flow for Analog Layout



# Design Case Study: LCD-Driver



NOTE: Both ICs by 'manual' and 'const-driven' implemented on NECEL 0.35um, both of them could work.  
(Collaboration with NEC micro systems.)



# Today's Talk

## 1) Rect. packing-base analog placement

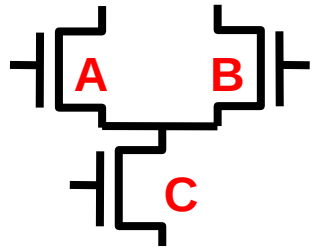
- ➔ Sequence-pair Packing
- ➔ Constraint-driven Optimization

## 2) With or without packing scenario, how do we develop analog placement?

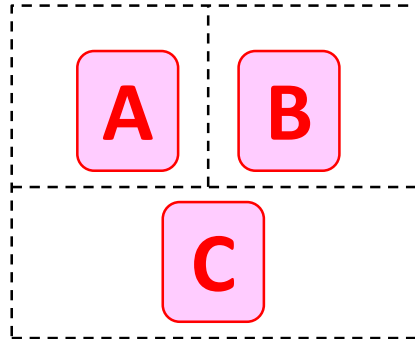
- ➔ Analytical Analog placement with proximity constraints
- ➔ Comparison : w/ and w/o topological packing technique



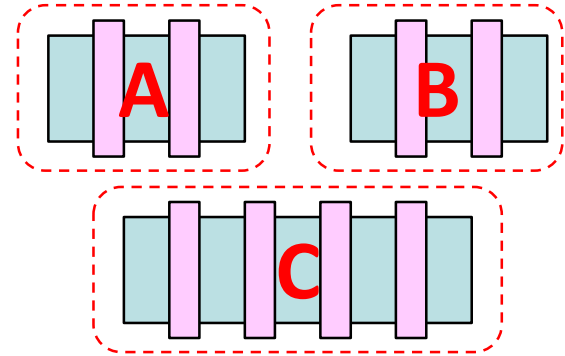
# Representation of Placement (1)



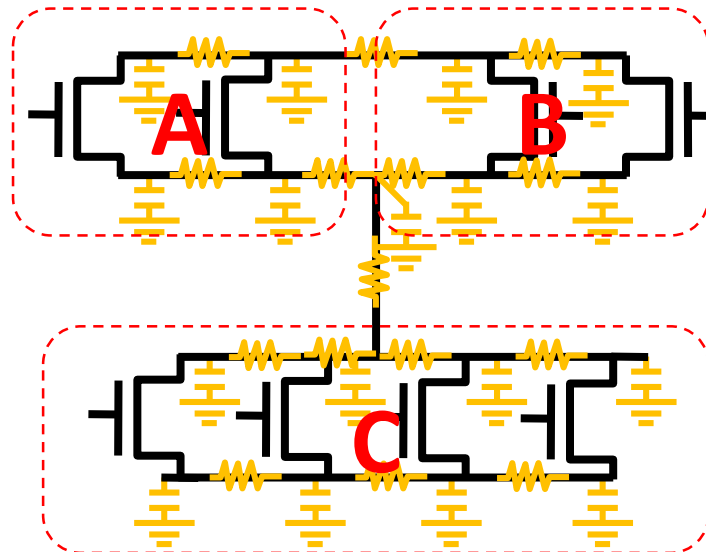
(1) Schematic



(2) Symbolic/Topological Placement



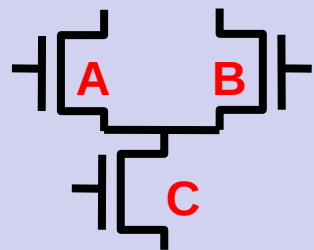
(3) Physical/Geometrical Placement



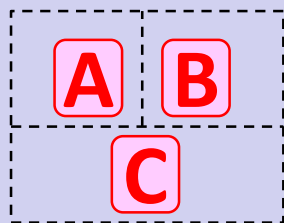
(4) Electrical Placement



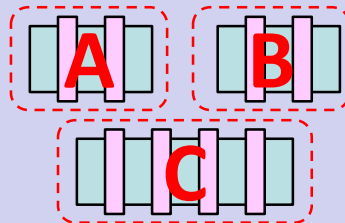
# Representation of Placement (2)



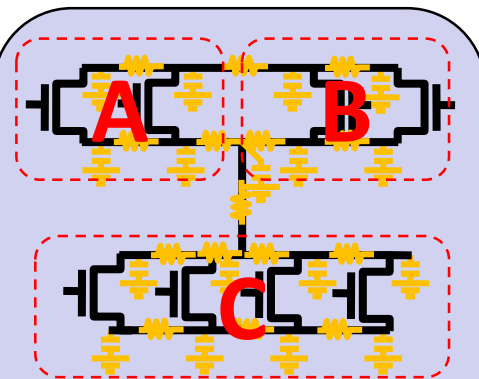
Schematic



Topological Placement



Geometrical Placement



Electrical Placement

## Outputs

Outline  
I/O pin  
Device size

Layers  
Design rules

Parasitics

## Steps

Device  
sizing

Floorpl  
anning

Device  
Generati  
on (PDK)

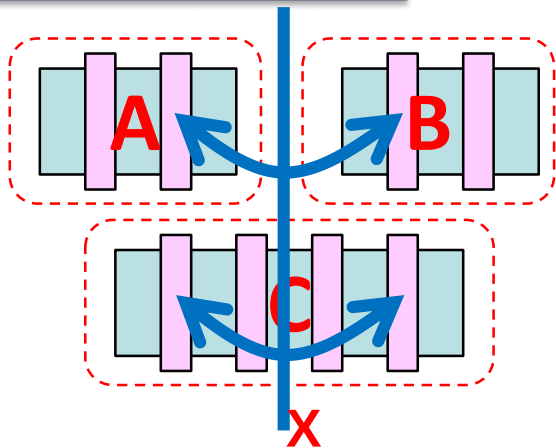
Layout(Place  
ment/Routing/  
Compaction)

LPE



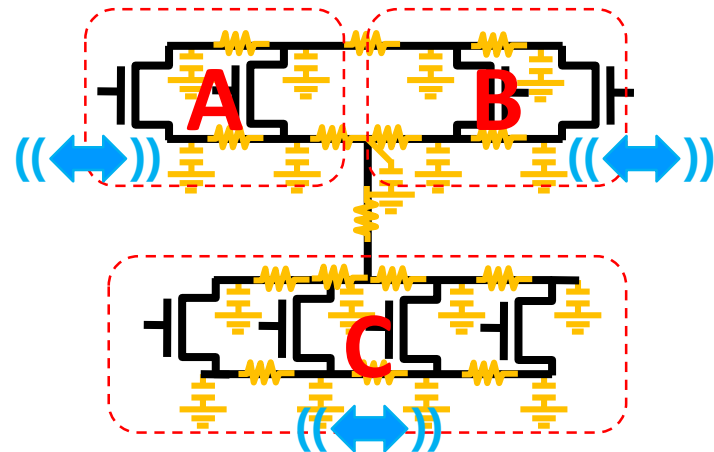
# Optimization of Placement

## Constraint-driven



1. Spec.:  $V_{off} < 1\text{mV}$
2. Extract diff. pair (A, B)
3. Symm. Const.: A and B is x-symmetry for X  
Input is up to here
4. Represent placement and constraint topologically
5. Search optimal placement under constraints

## Sensitivity-driven

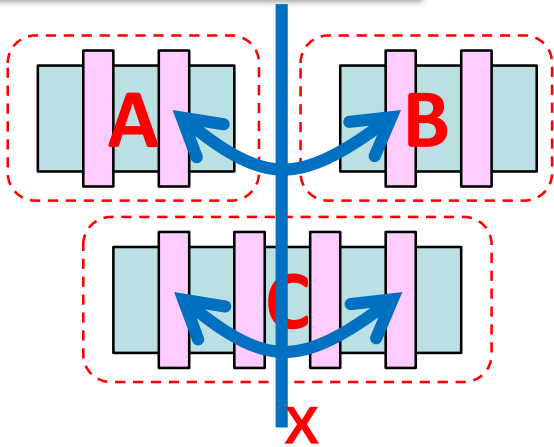


1. Spec.:  $V_{off} < 1\text{mV}$   
Input is up to here
2. Generate parasitic network
3. Sensitivity analysis  
$$\min\left(\frac{\partial V_{offset}}{\partial X_A} + \frac{\partial V_{offset}}{\partial X_B} + \frac{\partial V_{offset}}{\partial X_C}\right)$$
4. Perturb placement of A, B, C and optimize placement



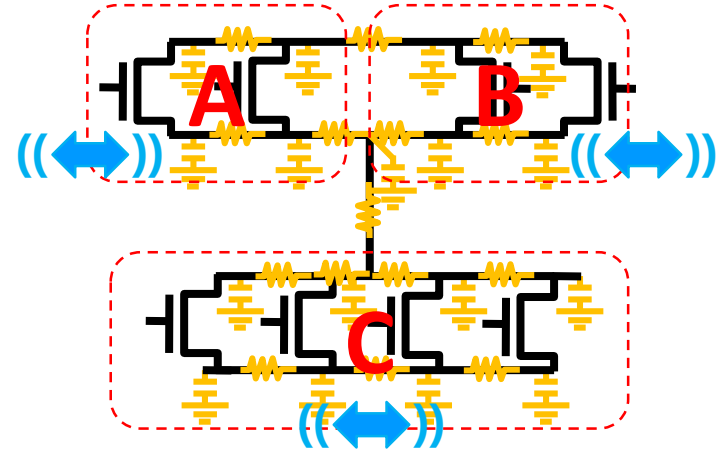
# Constraint-driven v.s. Sensitivity-driven

## Constraint-driven



- Need to substitute objective and constraints
- Available to use general optimizer like SA
- Rapid computation and global optimization
- EDA and users can have explicit consensus by means of constraints

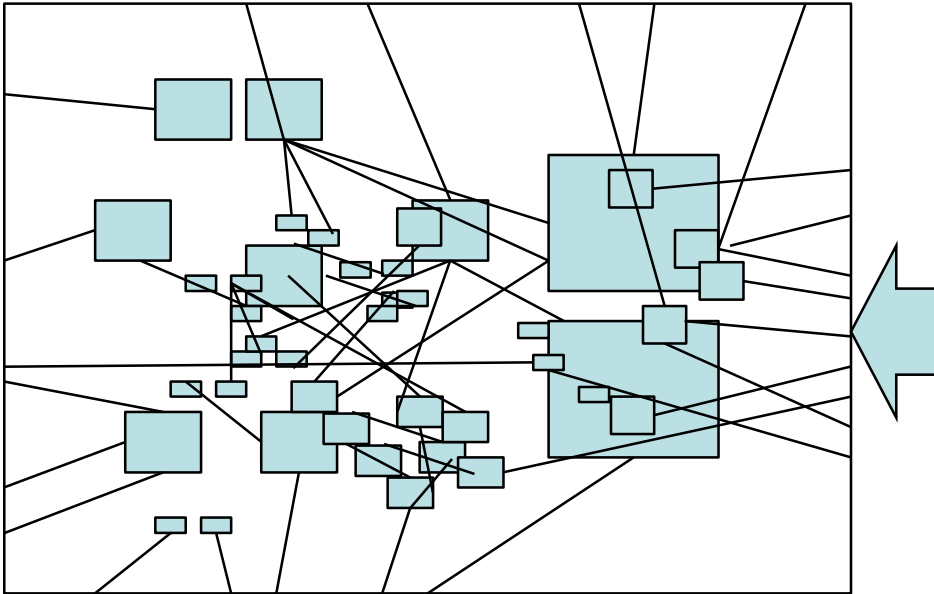
## Sensitivity-driven



- Directly optimize specification without substituting objective and constraints
- Huge computation and local optimization
- All can be done in EDA
- Need routing information for accuracy



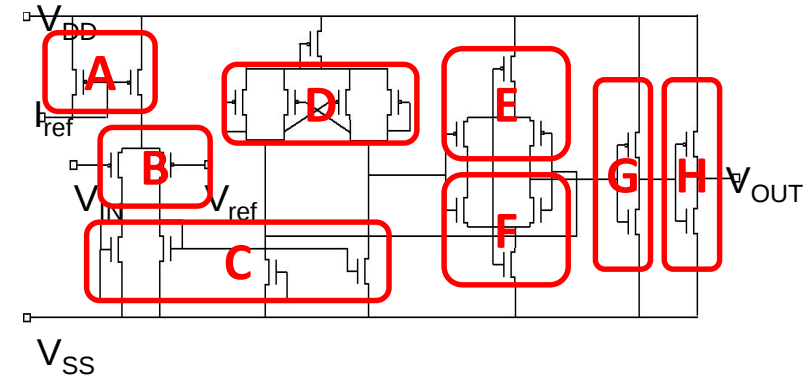
# Preliminary of Sensitivity-driven: Analytical Analog Placement



Analytical Placement

Pros: high speed, good scalability

Cons: many overlaps, messy



Proximity function induced by group information

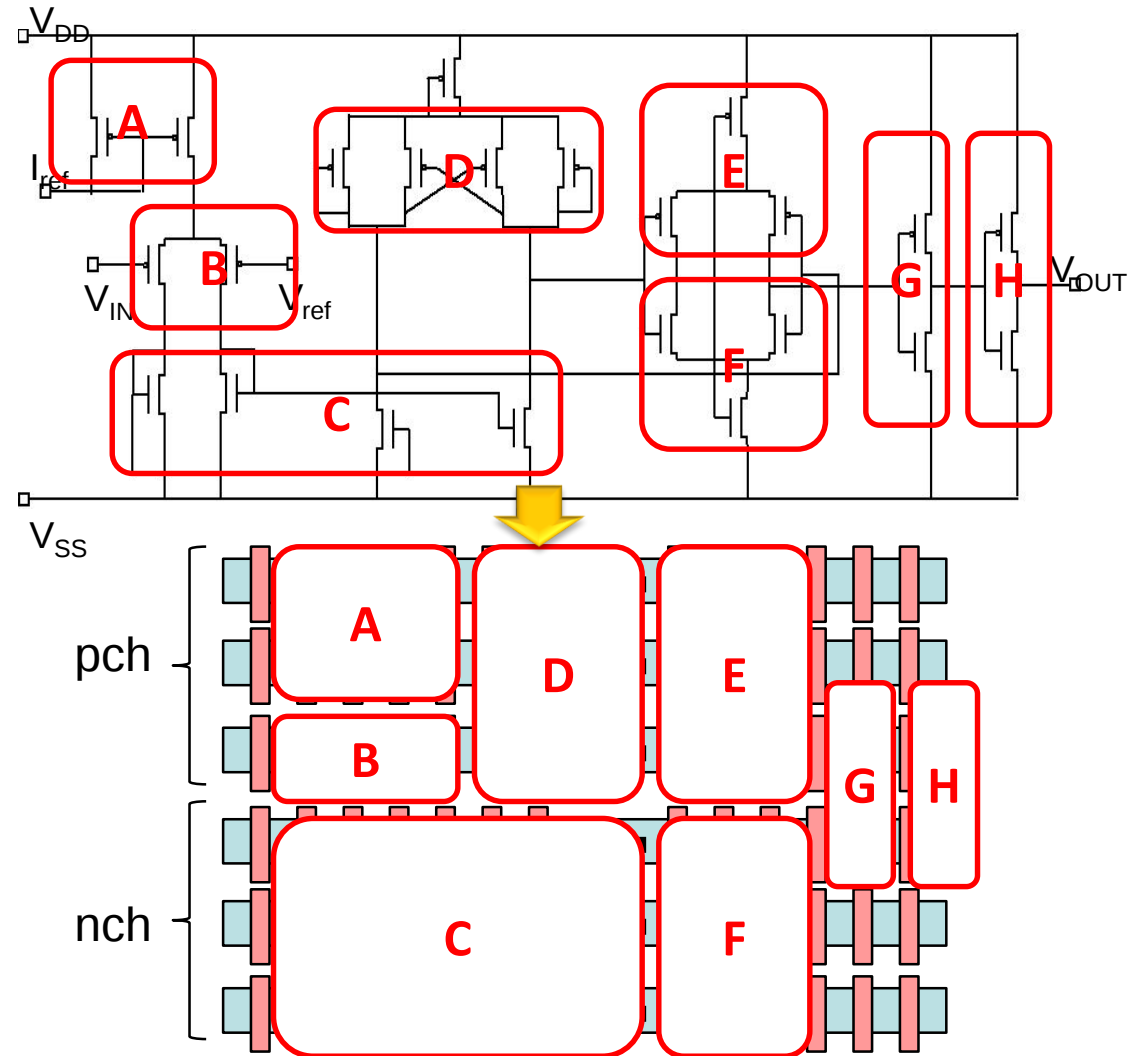
**Analytical analog placement w/ proximity constraints**



# Group Extraction from Schematic

1. Extract sub-netlist corresponding to current mirror, differential pair, logic primitive...

2. Place blocks corresponding to sub-netlists.



# w/o Rect. Packing: Analytical Formulation

**Min: CostOfHPWL + CostOfOverlap + CostOfGroupProximity**

Variables: x and y-coordinates of each cell

**CostOfHPWL  $\rightarrow$  LogSumExp.**

**CostOfHPWL  $\rightarrow$  Overlap Removal Length, Takashima, et. al. SASIMI 2010.**

**CostOfGroupProximity  $\rightarrow$  like an HPWL formulation.**

Well Group : P-well, N-well with same potential

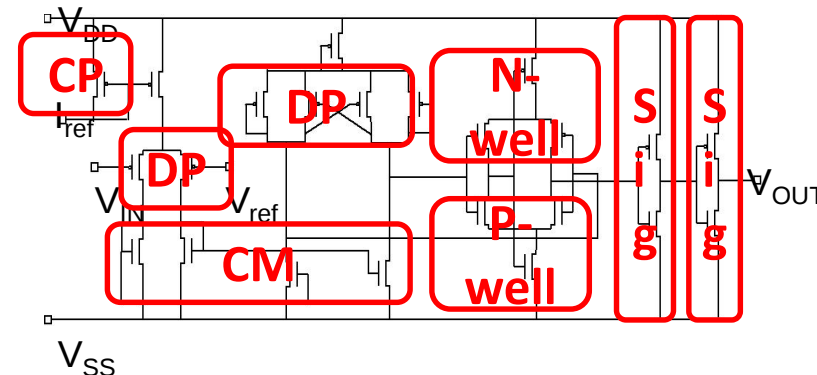
CM. Group : current mirrors

DP. Group : differential pairs

Signal Group : path from VDD to GND

Cap. Group : capacitances with same size

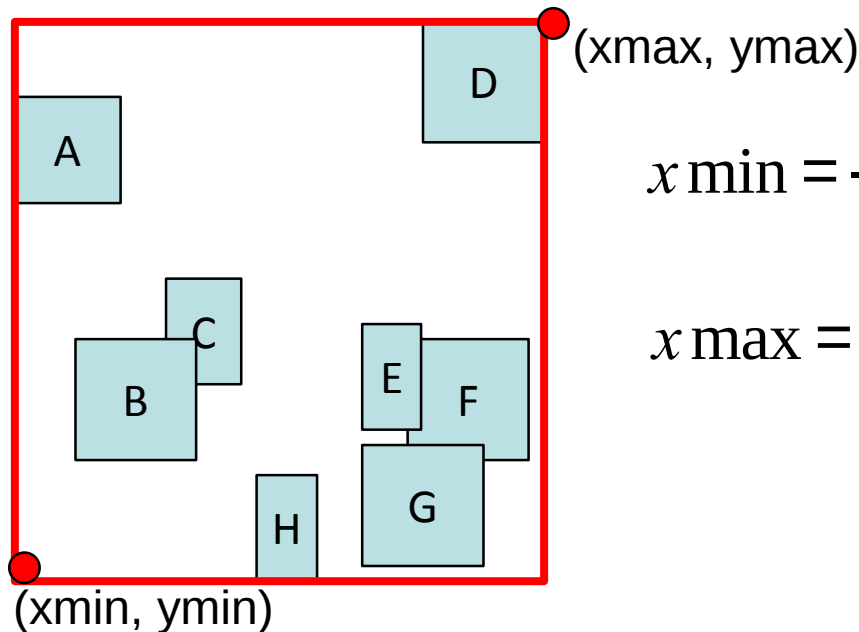
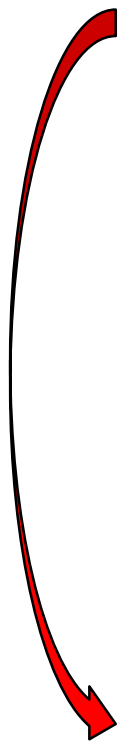
Res. Group : resistors connected in parallel or serial.



# Group Proximity Cost Formulation

**GroupCost = Max(AreaOfBoundingBox, SumOfCellArea)**

Group : { A, B, C, D, E, F, G, H }



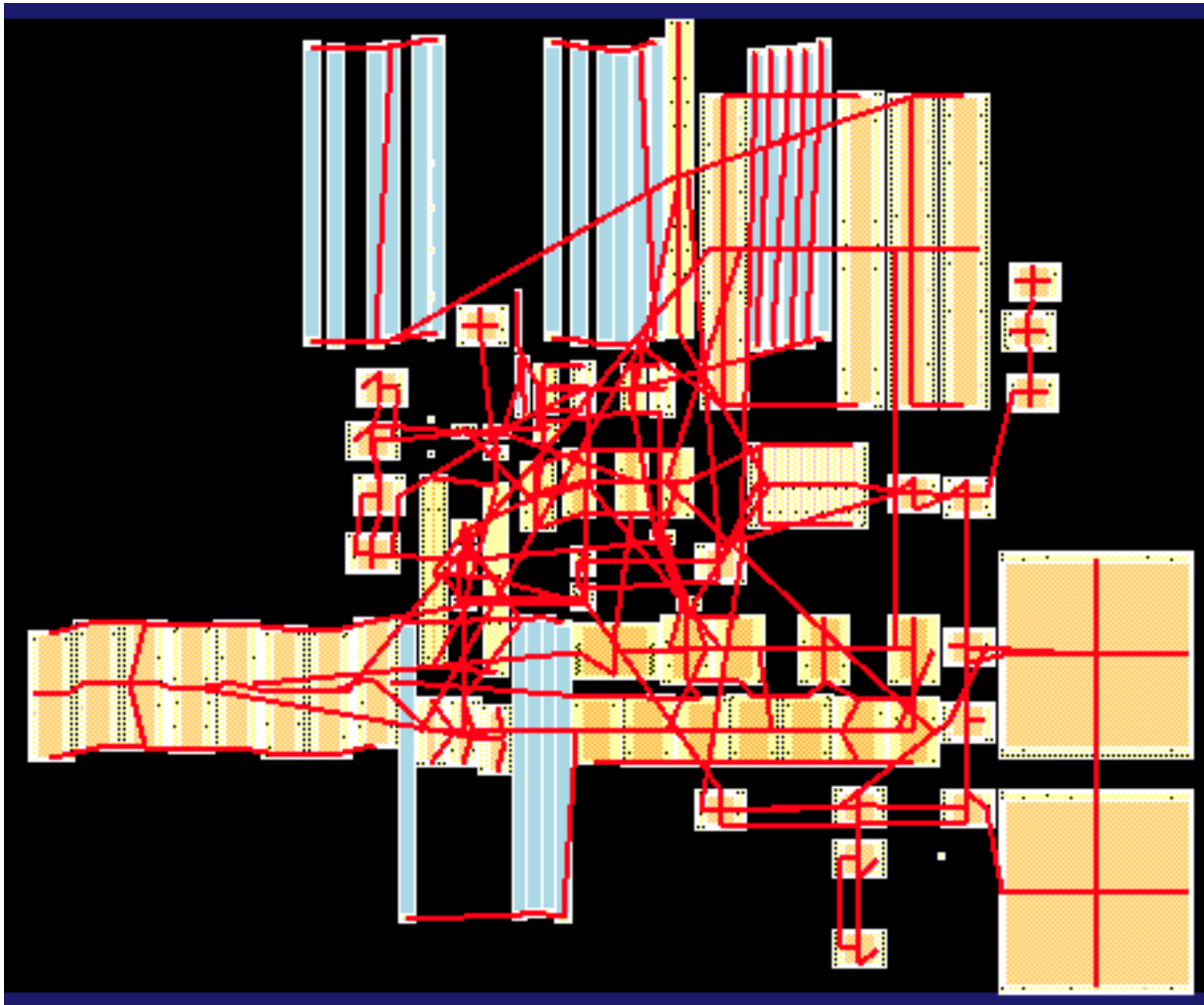
$$x_{\min} = -t \log \sum_{i \in \{A, \dots, H\}} \exp(-l(i)/t)$$

$$x_{\max} = t \log \sum_{i \in \{A, \dots, H\}} \exp(r(i)/t)$$

$$t \log \{ \exp((x_{\max} - x_{\min}) * (y_{\max} - y_{\min}) / t) + \exp(\sum_{i \in \{A, \dots, H\}} a(i) / t) \}$$



# Example: Analytical Analog Placement w/ proximity constraints

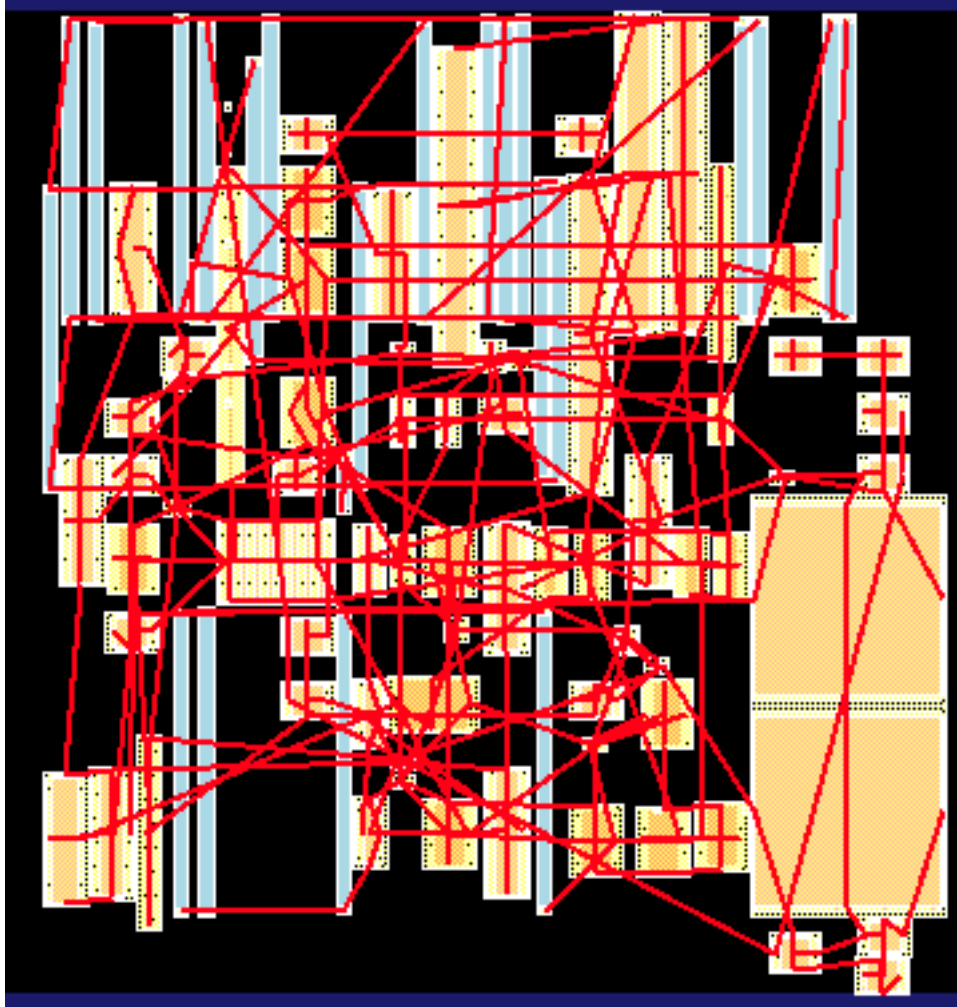


TIME : 1.0 sec.  
AREA : 29,793 (100%)  
HPWL : 2,998 (100%)

But, many DR-errors.



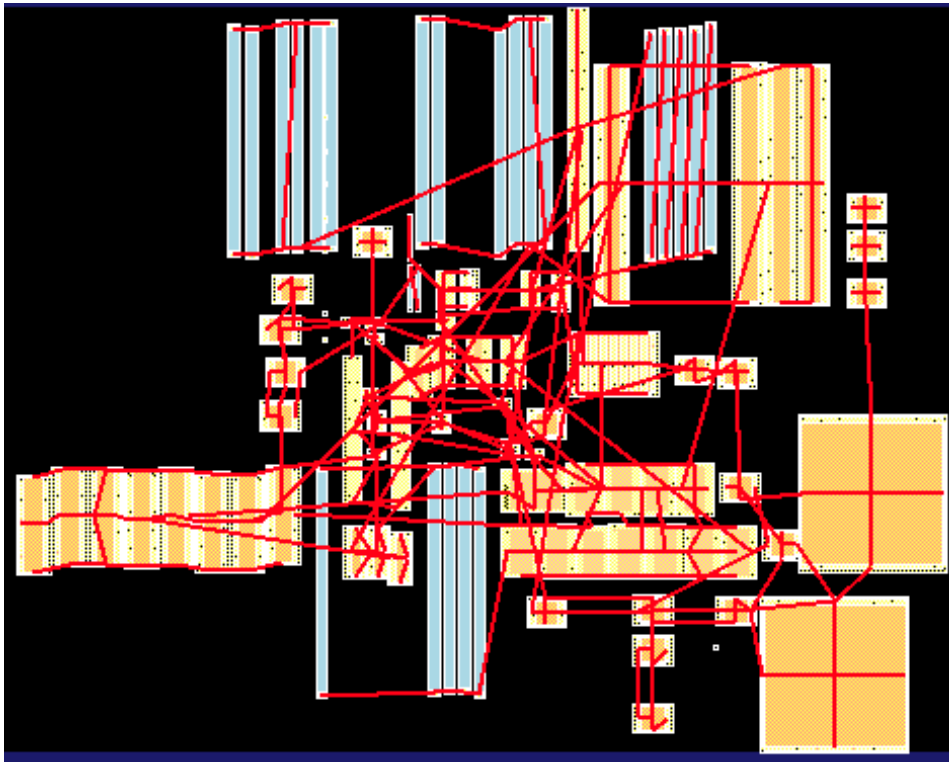
# Analytical Analog Placement w/o Proximity Constraints



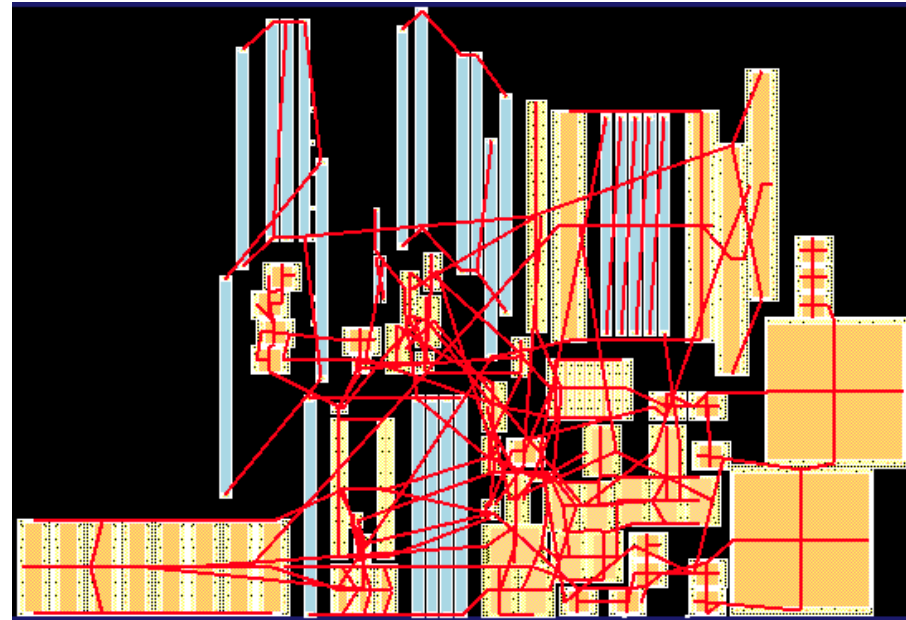
TIME : 1.0 sec.  
AREA : 22,637 (76%)  
HPWL : 4,259 (142%)



# Eliminating DR-errors



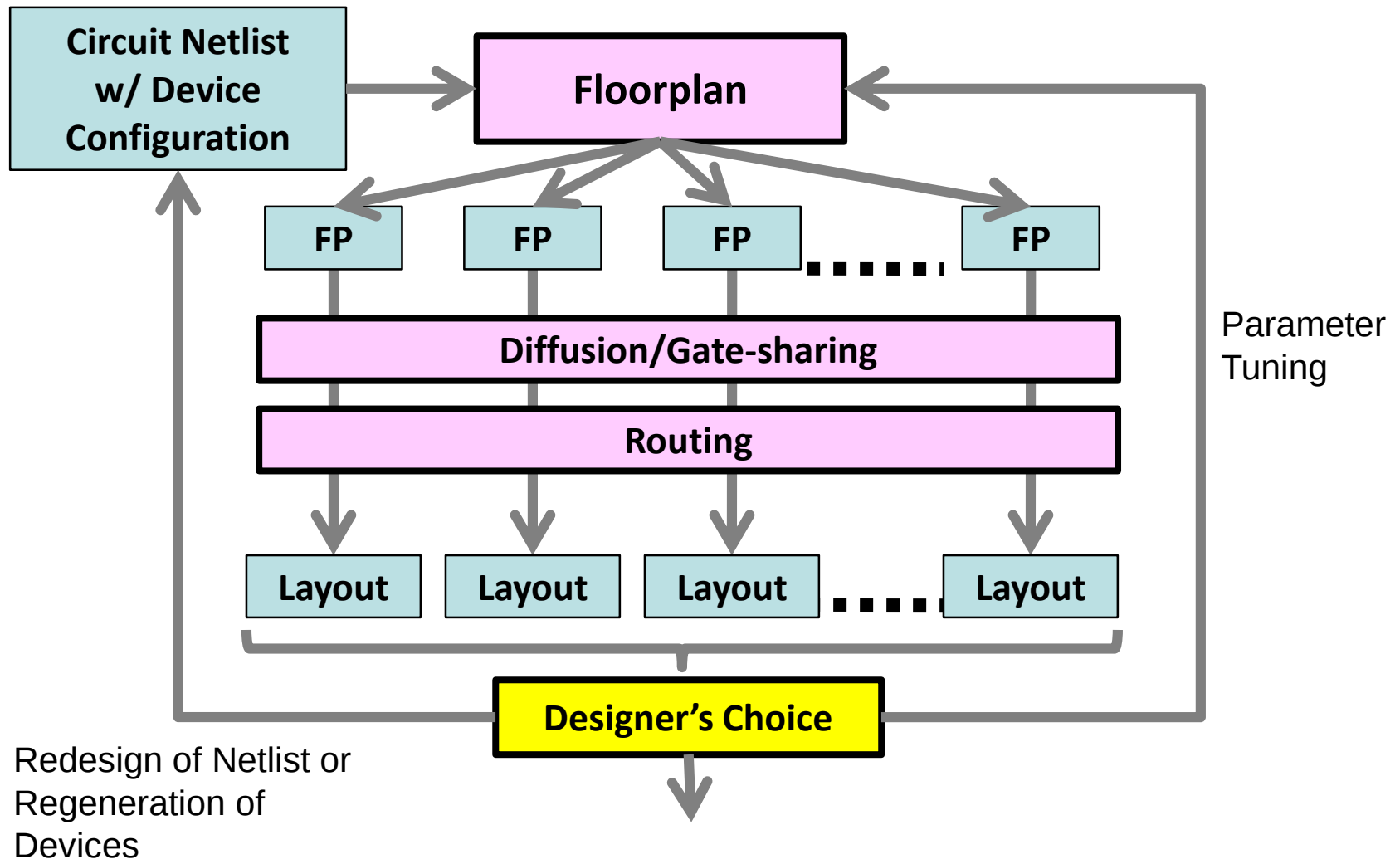
De-compaction  
No DR-errors.



1D-Compaction  
No DR-errors.

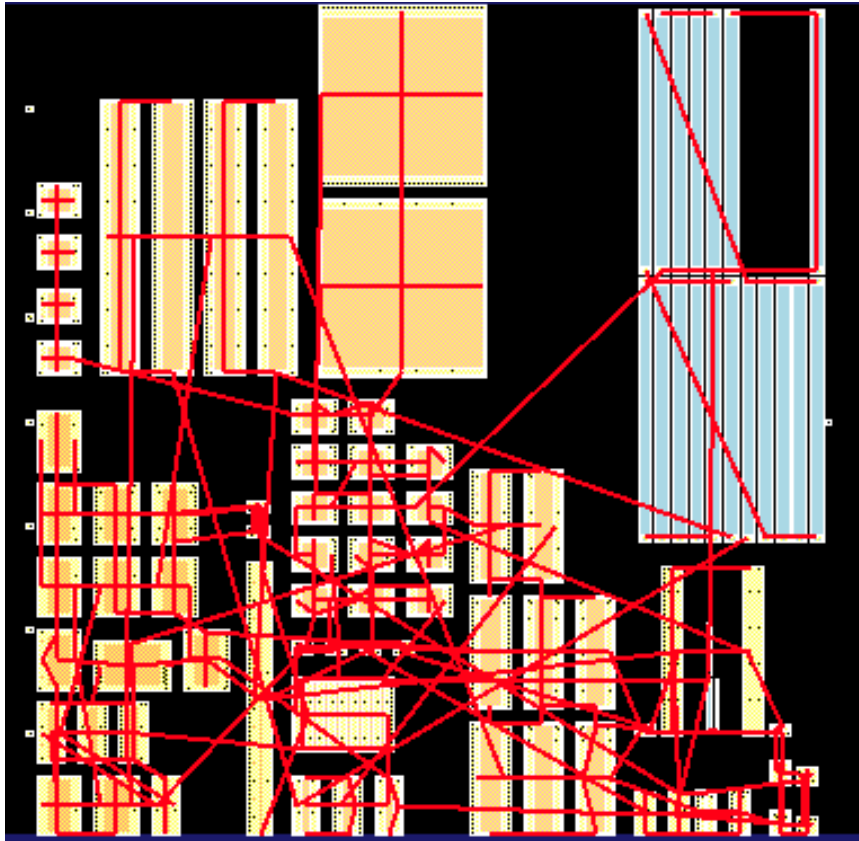


# w/ Rect. Packing: Multi-output Floorplan



# Comparison:

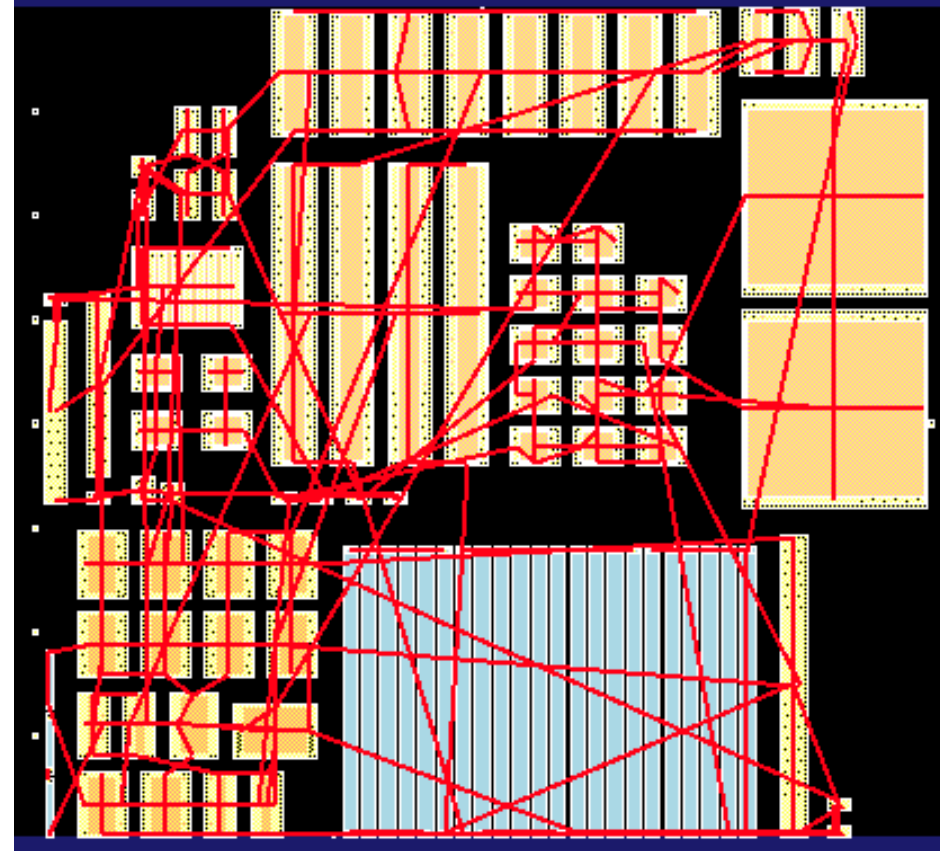
## Rect. Packing-base Placement (1)



AREA : 23,212 (78%)

HPWL : 3,443 (115%)

No DR-errors.



AREA: 25,405 (85%)

HPWL: 4,010 (134%)

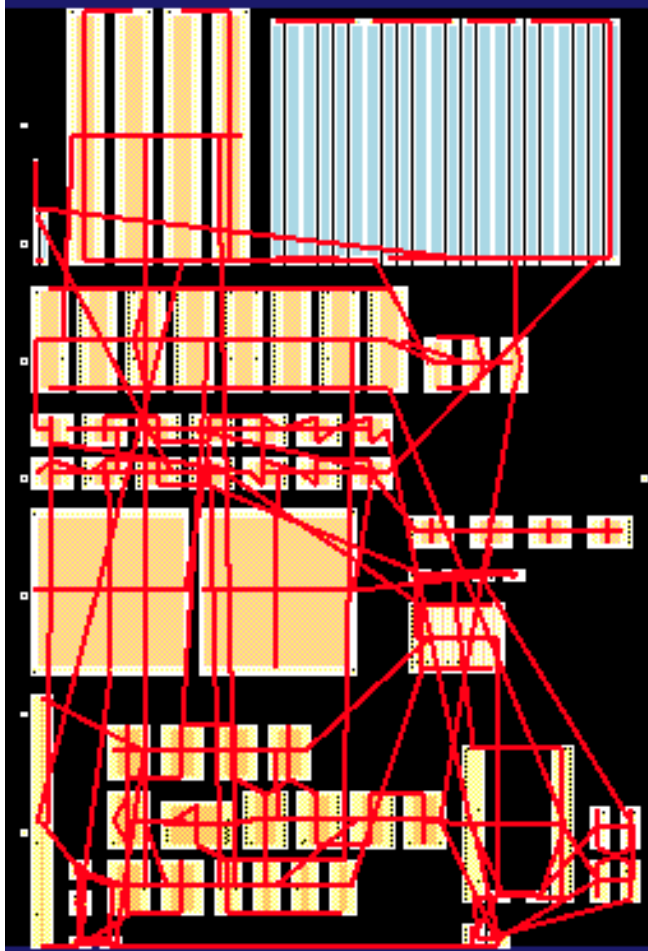
No DR-errors.

Total time for 10 placements: 7.0 sec.

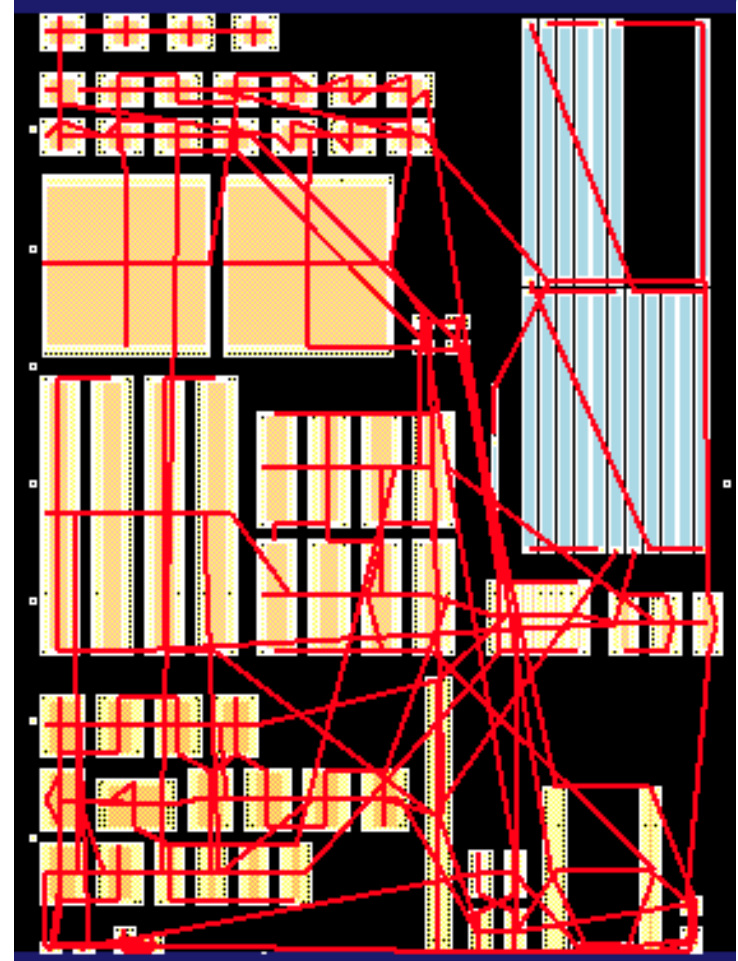


# Comparison:

## Rect. Packing-base Placement (2)



AREA : 27,070 (91%)  
HPWL : 3,814 (127%)  
No DR-errors.

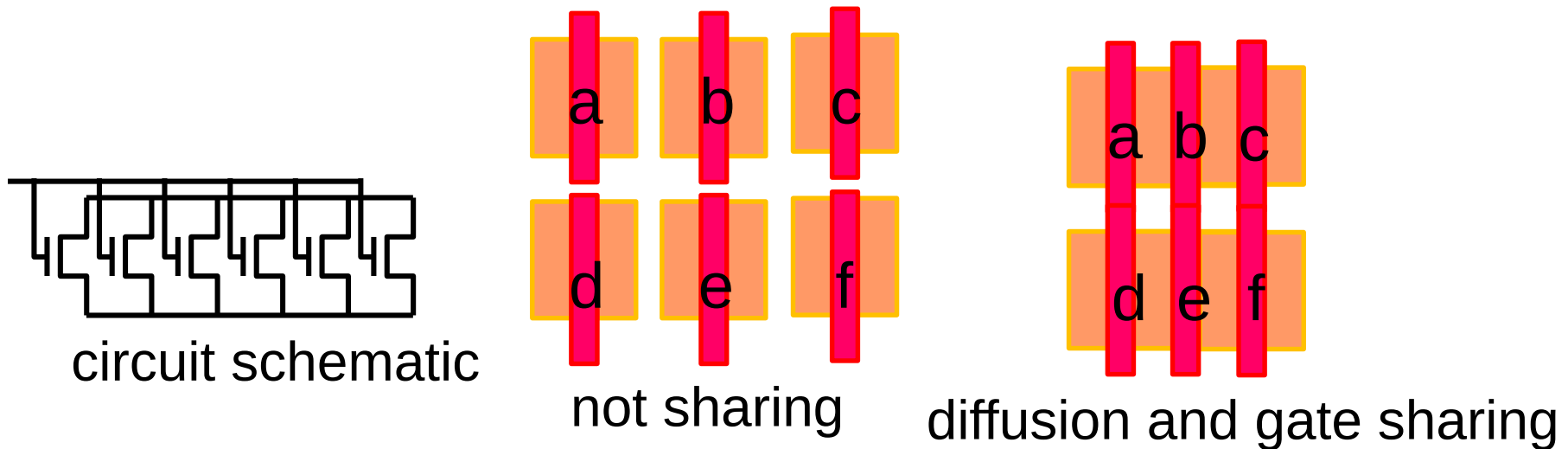


AREA : 26,798 (90%)  
HWPL : 4,083 (136%)  
No DR-errors.



# w/ Rect. Packing: Dynamic Diffusion/Gate Sharing

Diffusions (gates) can save area if they have the same net

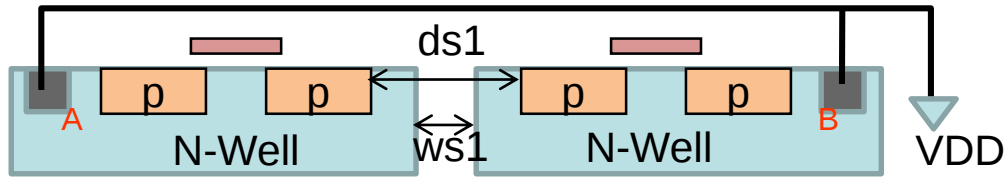


***possible gate/diffusion sharing:  
a set of blocks forming a topological row and array***

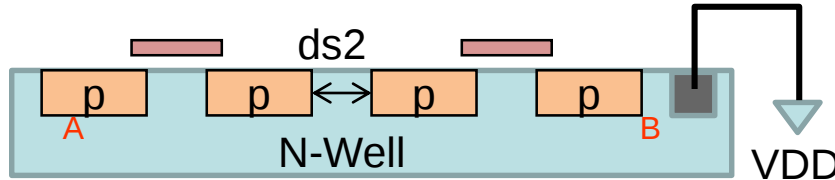


# w/ Rect. Packing: Dynamic Well Island Generation

## Different rules for separation between wells

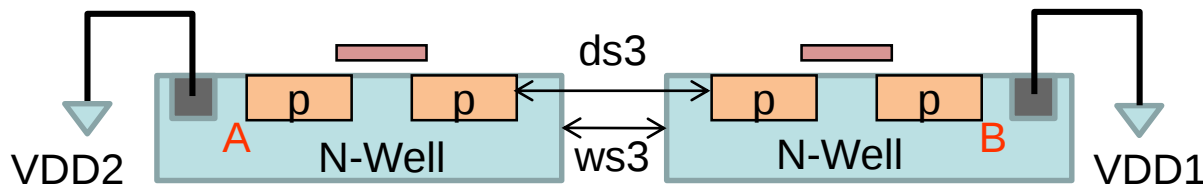


A and B have the same potential  $\rightarrow$  separation =  $ws1$



NOTE:  $ds2 < ws1 < ws2$

A and B have the same well island  $\rightarrow$  separation =  $ds2$  not for wells but diffusion



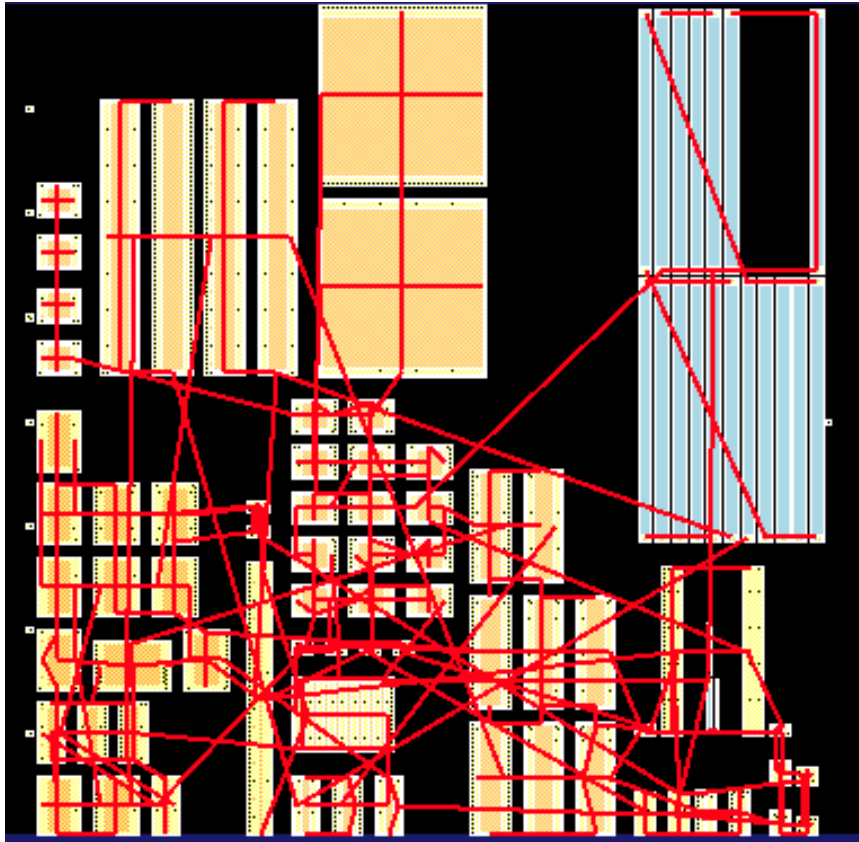
A and B have different potential wells  $\rightarrow$  separation =  $ws3$

***possible well-island :***

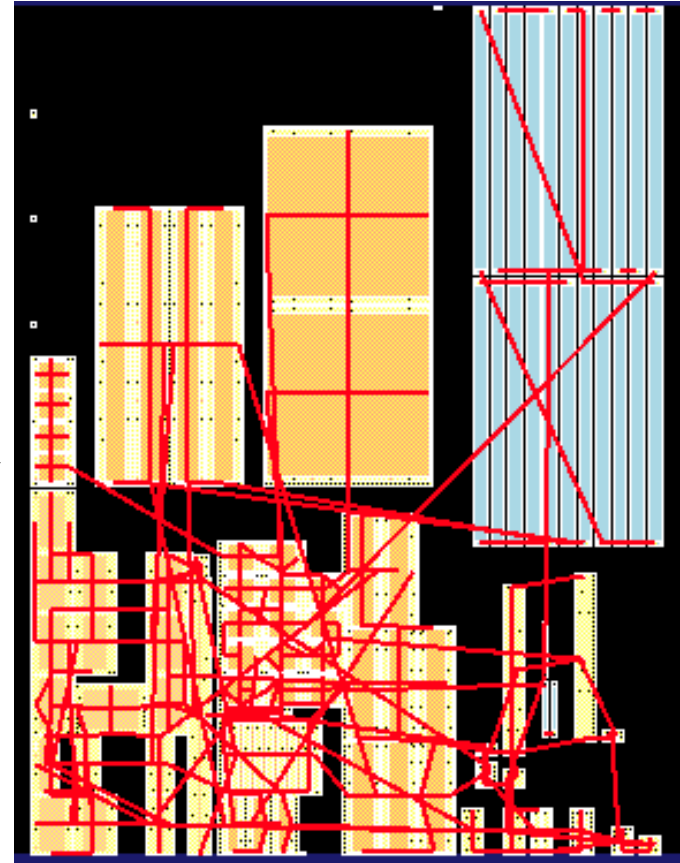
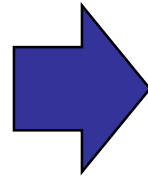
***a set of blocks which are rectangular extractable***



# Control of Adjacency: Diffusion Sharing



w/o diffusion sharing



w/ diffusion sharing



# Summary

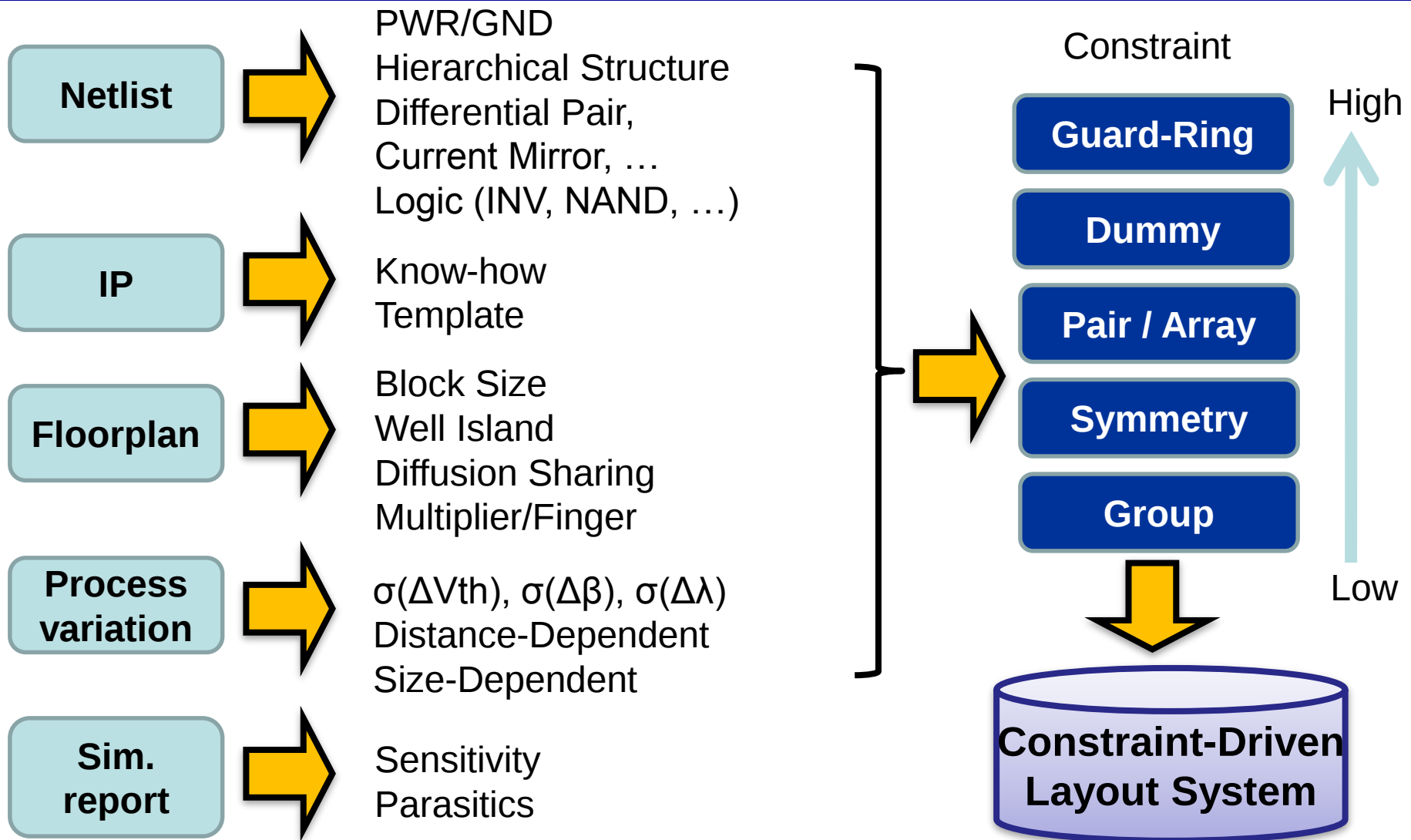
- Rect. Packing:
  - Compacted
  - Multi-output
  - Soft modules
  - No DR errors
  - Easy to take constraint-driven
  - **Easy to control adjacency (constraints)**
  - Floorplan to estimate area
- Analytical:
  - Less wire-length
  - Quick
  - Scalability
  - Potentially applicable to sensitivity-driven
  - Initial placement for manual designer



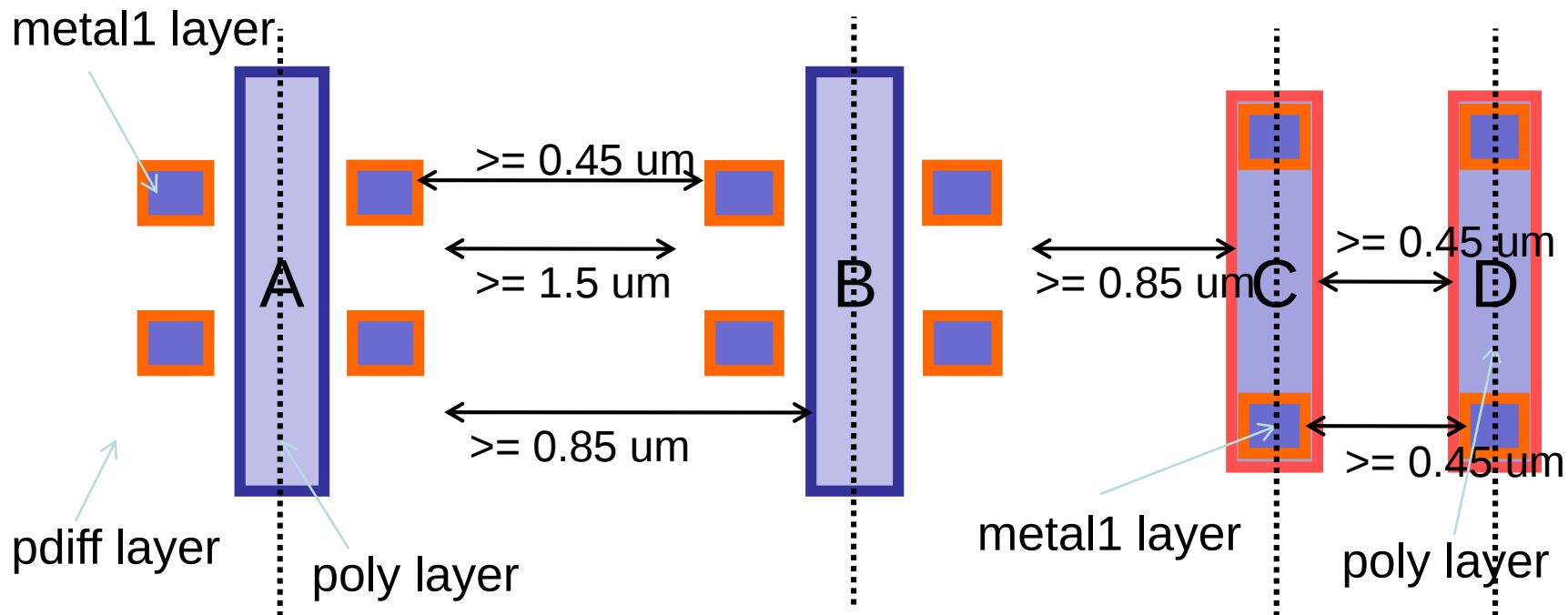
# Thank you!



# Analog Layout Constraint

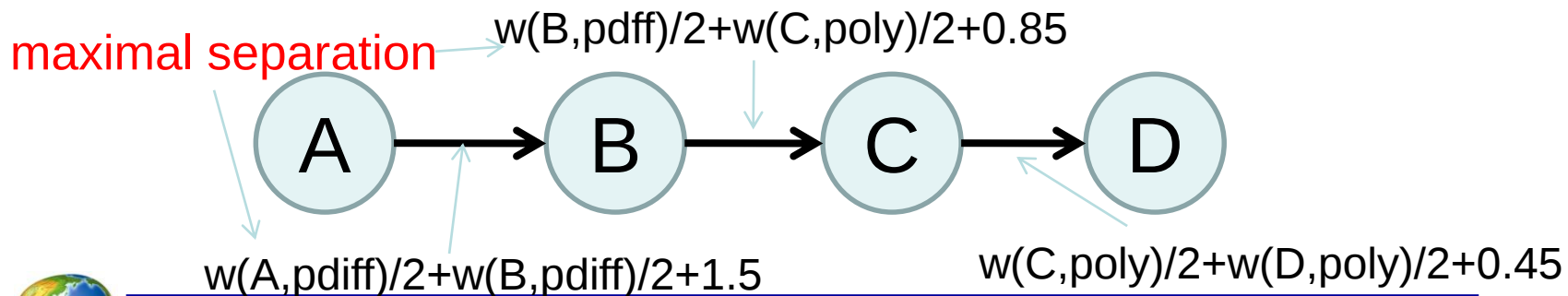


# Separation Constraint

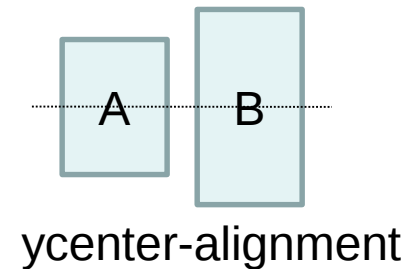
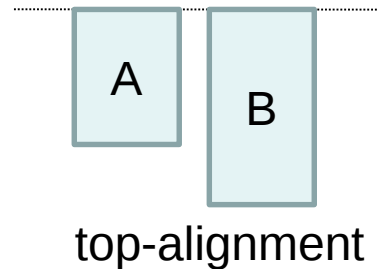
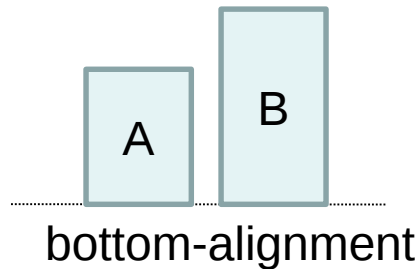


*horizontal constraint graph:*

NOTE:  $w(X, L)$  = width of layer  $L$  of device  $X$



# Alignment Constraint



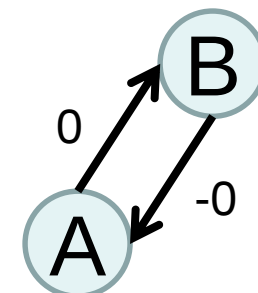
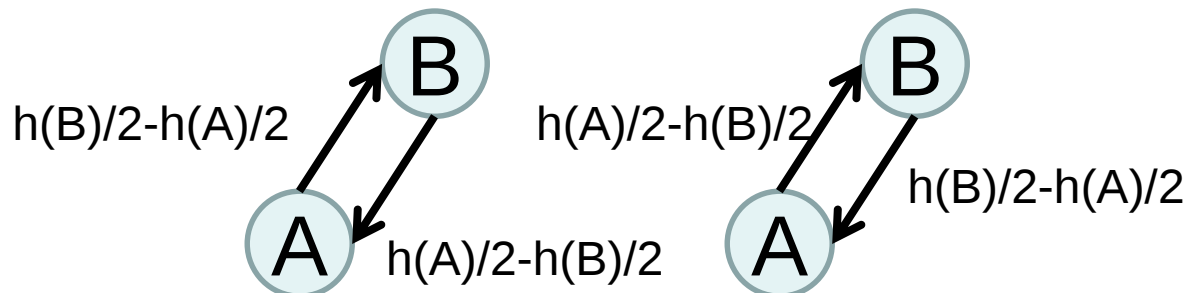
*sequence-pair condition:*

$$\alpha^{-1}(A) < \alpha^{-1}(B), \beta^{-1}(A) < \beta^{-1}(B) \quad \text{or} \quad \alpha^{-1}(B) < \alpha^{-1}(A), \beta^{-1}(B) < \beta^{-1}(A)$$

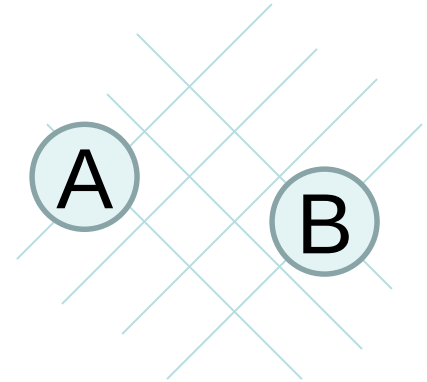
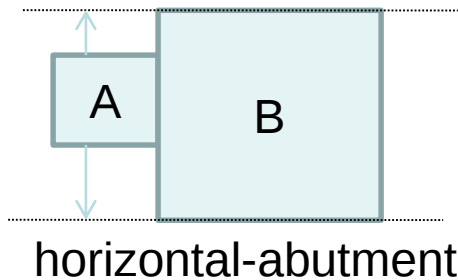
$$SP = (\dots A \dots B \dots, \dots A \dots B \dots)$$

$$SP = (\dots B \dots A \dots, \dots B \dots A \dots)$$

*vertical constraint graph:*



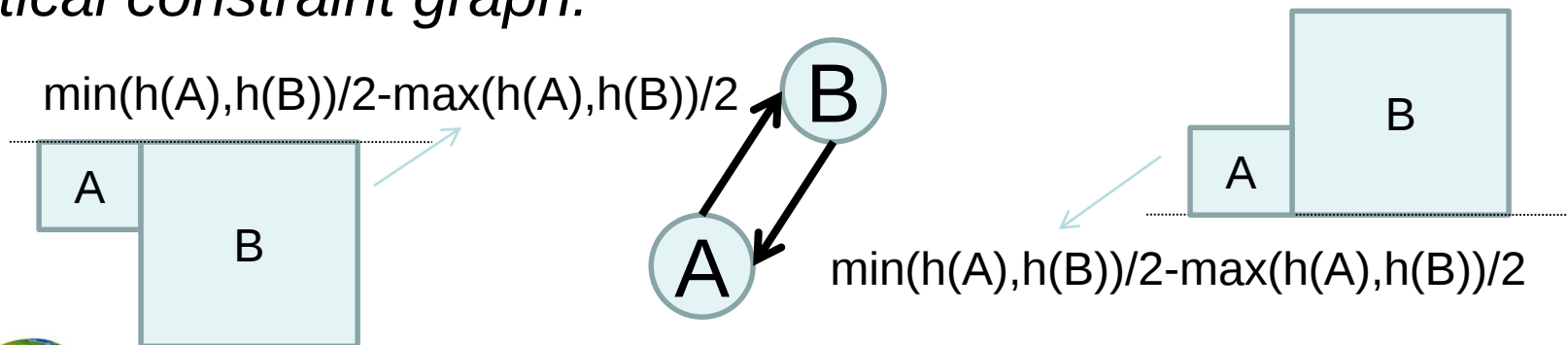
# Abutment Constraint



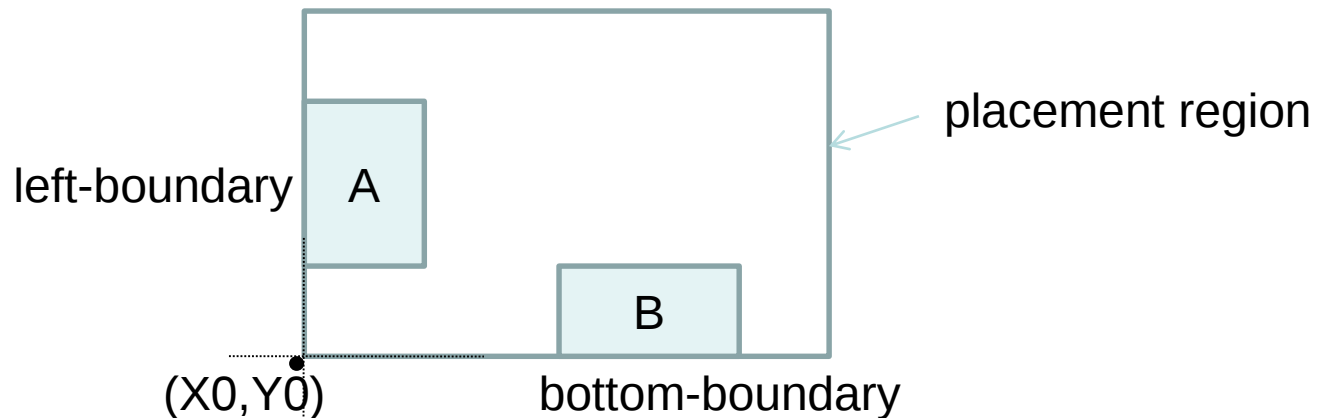
*sequence-pair condition:*

$$\alpha^{-1}(A) < \alpha^{-1}(B), \beta^{-1}(A) < \beta^{-1}(B) \quad \text{and} \quad \alpha^{-1}(X) < \alpha^{-1}(A) \text{ or } \alpha^{-1}(B) < \alpha^{-1}(X) \text{ or} \\ \beta^{-1}(X) < \beta^{-1}(A) \text{ or } \beta^{-1}(B) < \beta^{-1}(X) \\ \text{for } \forall X (\neq A, B)$$

*vertical constraint graph:*



# Boundary Constraint

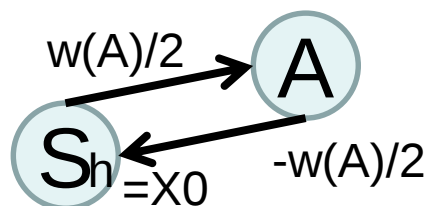


*sequence-pair condition:*

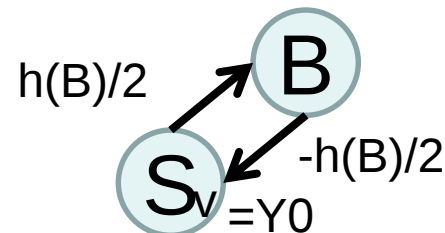
$$\alpha^{-1}(A) < \alpha^{-1}(X) \quad \text{or} \quad \beta^{-1}(A) < \beta^{-1}(X) \quad \text{for} \quad \forall X (\neq A)$$

$$\alpha^{-1}(X) < \alpha^{-1}(B) \quad \text{or} \quad \beta^{-1}(B) < \beta^{-1}(X) \quad \text{for} \quad \forall X (\neq B)$$

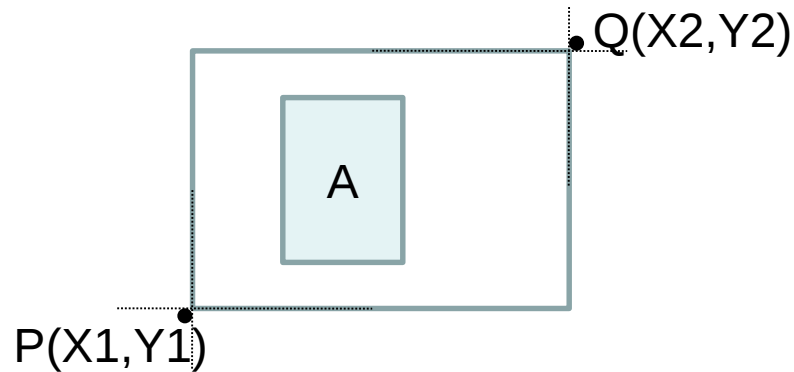
*horizontal constraint graph:*



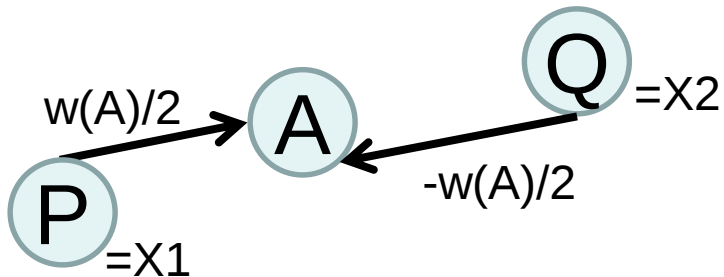
*vertical constraint graph:*



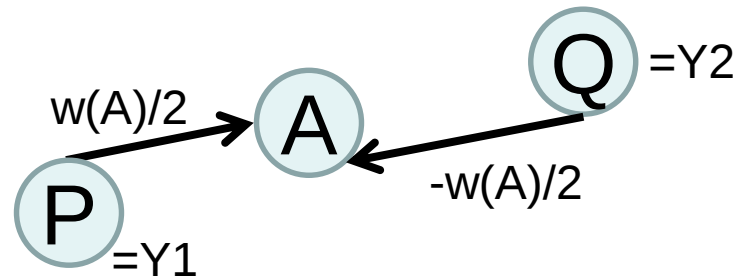
# Range Constraint



*horizontal constraint graph:*



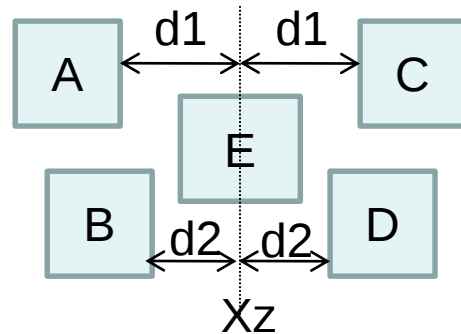
*vertical constraint graph:*



NOTE: P, Q are dummy blocks  
range const.  $\rightarrow$  preplaced const. if P and Q are the same as A



# Symmetry Constraint



horizontal symmetry group  
 pair-symmetry: (A,C), (B,D)  
 self-symmetry: E

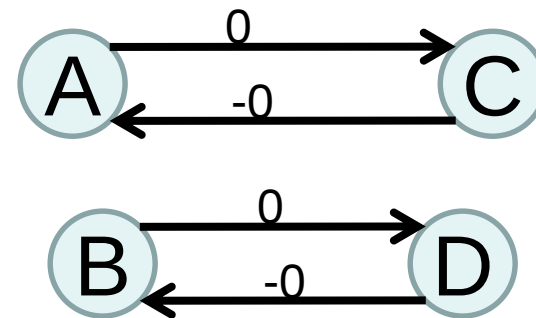
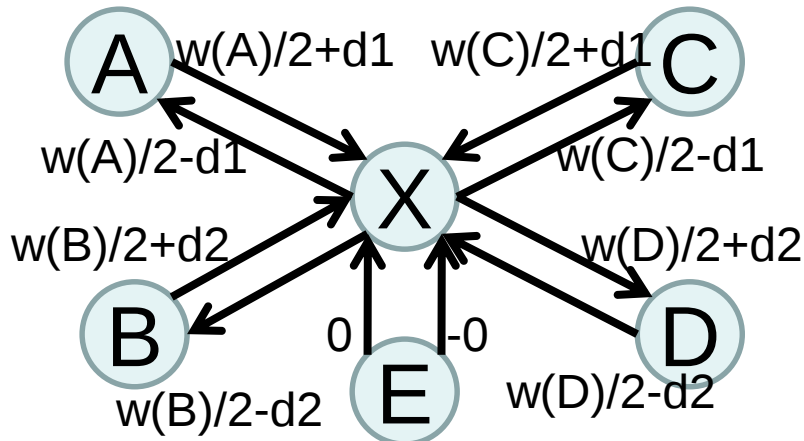
*sequence-pair condition:*

**NOTE:**  $\text{sym}(A)=C$ ,  $\text{sym}(B)=D$ ,  $\text{sym}(E)=E$

$$\alpha^{-1}(A) < \alpha^{-1}(B) \Leftrightarrow \beta^{-1}(\text{sym}(B)) < \beta^{-1}(\text{sym}(A))$$

*horizontal constraint graph:*

*vertical constraint graph:*



**NOTE:** ycenter-alignment

**NOTE:** X is dummy node, d1, d2 should be precalculated



# Cluster Constraint(1)

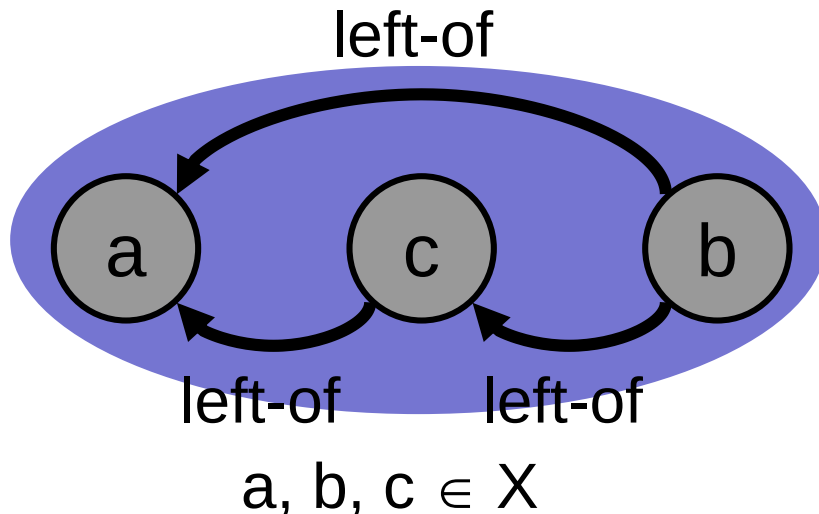
Horizontal-Convex:

For any pair (a, b) in X such that “a” is left-of “b”:

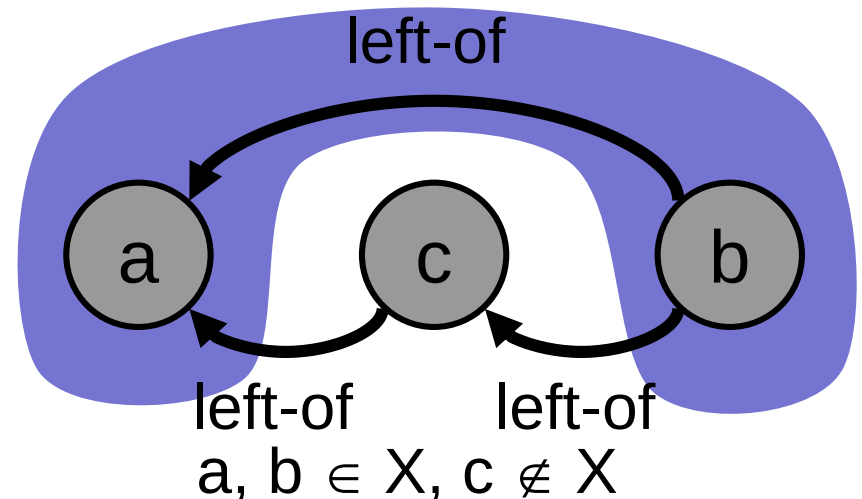
Any device “c” such that

“a” is left-of “c” and “c” is left-of “b” also belongs to X

Horizontal-convex



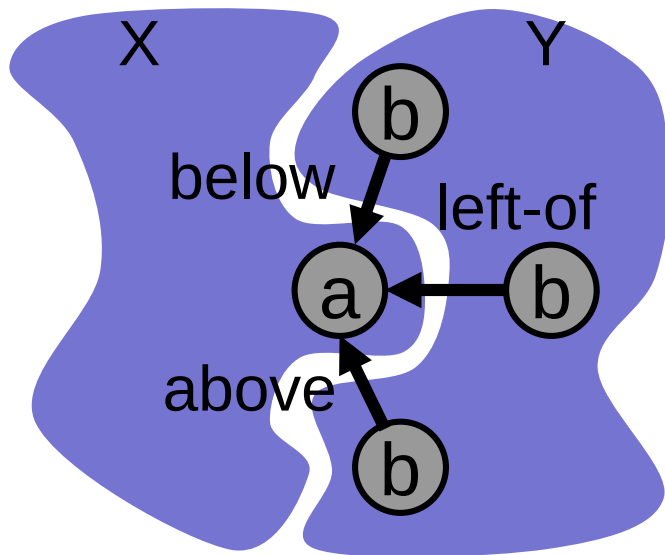
Not Horizontal-convex



# Cluster Constraint(2)

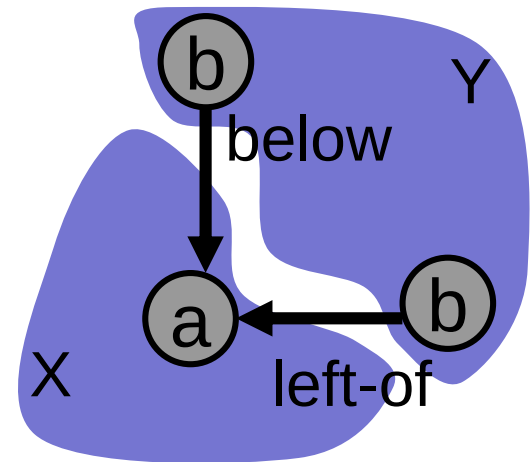
X is Convexly left-of Y:

- X and Y are horizontal-convex
- No pair (a, b) such that  $a \in X$  is right-of  $b \in Y$



X is convexly left-below Y:

- X is convexly left-of and convexly below Y
- No pair (a, b) such that  $a \in X$  is right-of and above  $b \in Y$



# Cluster Constraint(4)

*sequence-pair condition for all convex relation*

| X is convexly ... Y | Sequence-Pair $\forall a \in X$ and $\forall b \in Y$                        |
|---------------------|------------------------------------------------------------------------------|
| left-of             | $\{\alpha^{-1}(a) < \alpha^{-1}(b)\} \cup \{\beta^{-1}(a) < \beta^{-1}(b)\}$ |
| below               | $\{\alpha^{-1}(a) > \alpha^{-1}(b)\} \cup \{\beta^{-1}(a) < \beta^{-1}(b)\}$ |
| right-of            | $\{\alpha^{-1}(a) > \alpha^{-1}(b)\} \cup \{\beta^{-1}(a) > \beta^{-1}(b)\}$ |
| above               | $\{\alpha^{-1}(a) < \alpha^{-1}(b)\} \cup \{\beta^{-1}(a) > \beta^{-1}(b)\}$ |
| left-below          | $\beta^{-1}(a) < \beta^{-1}(b)$                                              |
| right-below         | $\alpha^{-1}(a) > \alpha^{-1}(b)$                                            |
| right-above         | $\beta^{-1}(a) > \beta^{-1}(b)$                                              |
| left-above          | $\alpha^{-1}(a) < \alpha^{-1}(b)$                                            |

